

# X-ray SR monitor (Fresnel Zone Plate (FZP) monitor)

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1. Principle of FZP monitor
2. Setup of FZP monitor
3. Measurement results
4. Summary

# Apparatus of Fresnel Zone Plate (FZP) monitor

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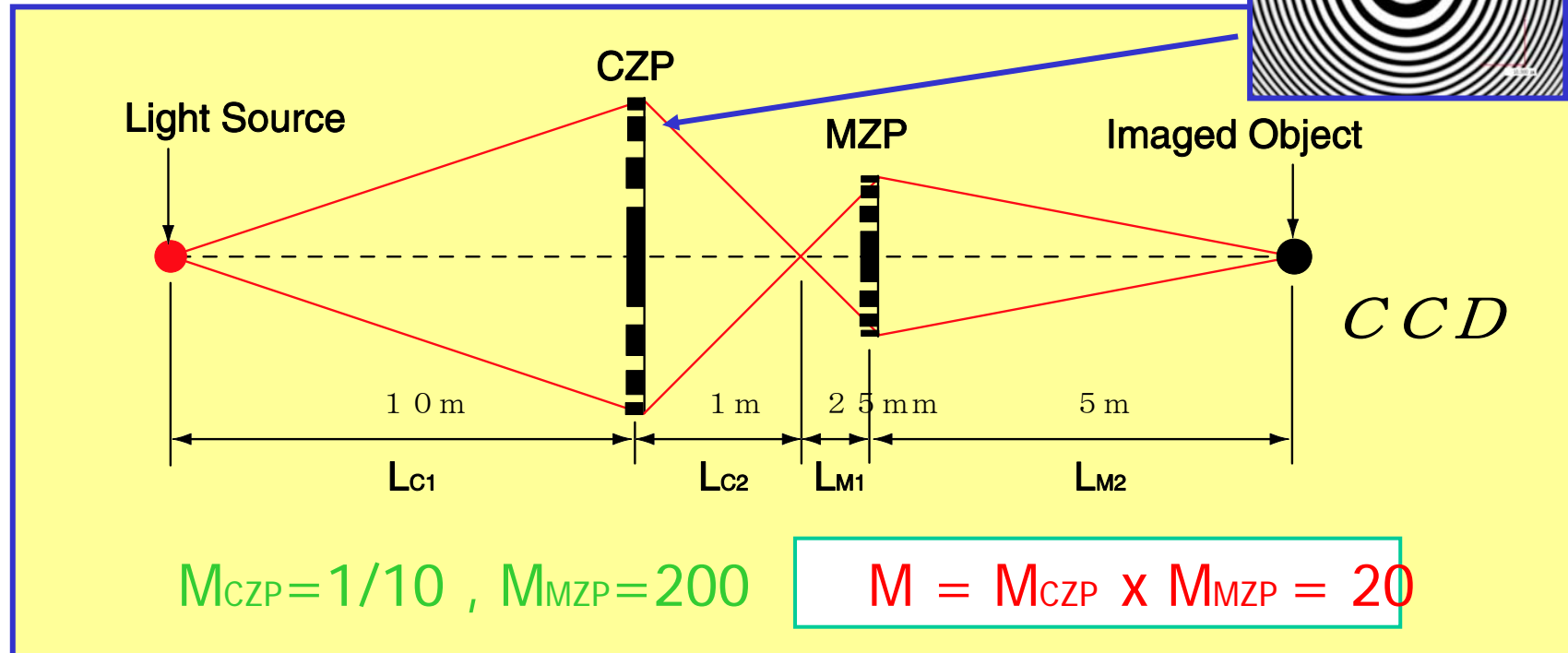
- Motivation

- The FZP monitor is aimed to measure the small electron beam size (<10 $\mu$ m) appeared at the ultra low emittance ring like linear-collider damping ring , 3rd generation synchrotron light source and future light sources like ERL (Energy Recovery Linac).

- Features

- High spatial resolution (<1  $\mu$ m)
- Non-destructive measurement
- 2-dimentional (x,y) beam profiling
- Real time beam profile measurement (<1ms)

# Principle of FZP monitor



- Monochromated **X-ray SR(3.235keV)** from bending magnet is used.  
→ Reduce the diffraction limit from SR-light.
- **Two Fresnel zone plates (FZPs)** are used  
→ The 20 times magnified beam image is obtained at X-CCD.

# Fresnel Zone Plate (FZP)



$$r_n = \sqrt{nf\lambda}$$

$\lambda$ : wave length

$n$ : zone number

$f$ : focal length

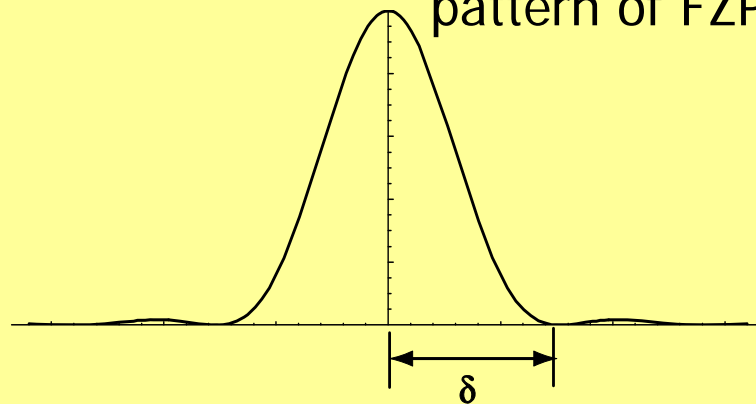
$$\delta = 1.22 \Delta r_N \approx 3\sigma$$

$$\Delta r_N = \frac{1}{2} \sqrt{\frac{f\lambda}{N}} = \frac{f\lambda}{2r_N}$$

$\Delta r_N$ : Most outer zone width

Airy pattern

Diffraction pattern of FZP



Parameters	CZP	MZP
Number of zone: N	6444	146
Radius of FZP	1500 $\mu\text{m}$	37.3 $\mu\text{m}$
Most outer zone width : $\Delta r_N$	116nm	128nm
Focal length: f	909mm	24.9mm

Spatial resolution is determined by **most outer zone width** of FZPs

# Total spatial resolution of FZP monitor

Parameters	Definition	Resolution( $1\sigma$ )
Diffraction limit (3.235keV)	$\lambda/4\pi\sigma_{SR}$	0.24 <sup>1)</sup> [ $\mu\text{m}$ ]
CZP ( $\Delta r_N=116\text{nm}$ )	$\sigma_{CZP} / M_{CZP}$	<u>0.55</u> [ $\mu\text{m}$ ]
MZP ( $\Delta r_N=124\text{nm}$ )	$\sigma_{MZP} / (M_{CZP} \times M_{MZP})$	0.002 [ $\mu\text{m}$ ]
CCD (1 pixel= $24\mu\text{m} \times 24\mu\text{m}$ )	$\sigma_{CCD} / (M_{CZP} \times M_{MZP})$	0.35 [ $\mu\text{m}$ ]
Total	--	<b>0.7</b> [ $\mu\text{m}$ ]

$$M_{CZP} = 1/10, M_{MZP} = 200, M_{CZP} \times M_{MZP} = 20$$

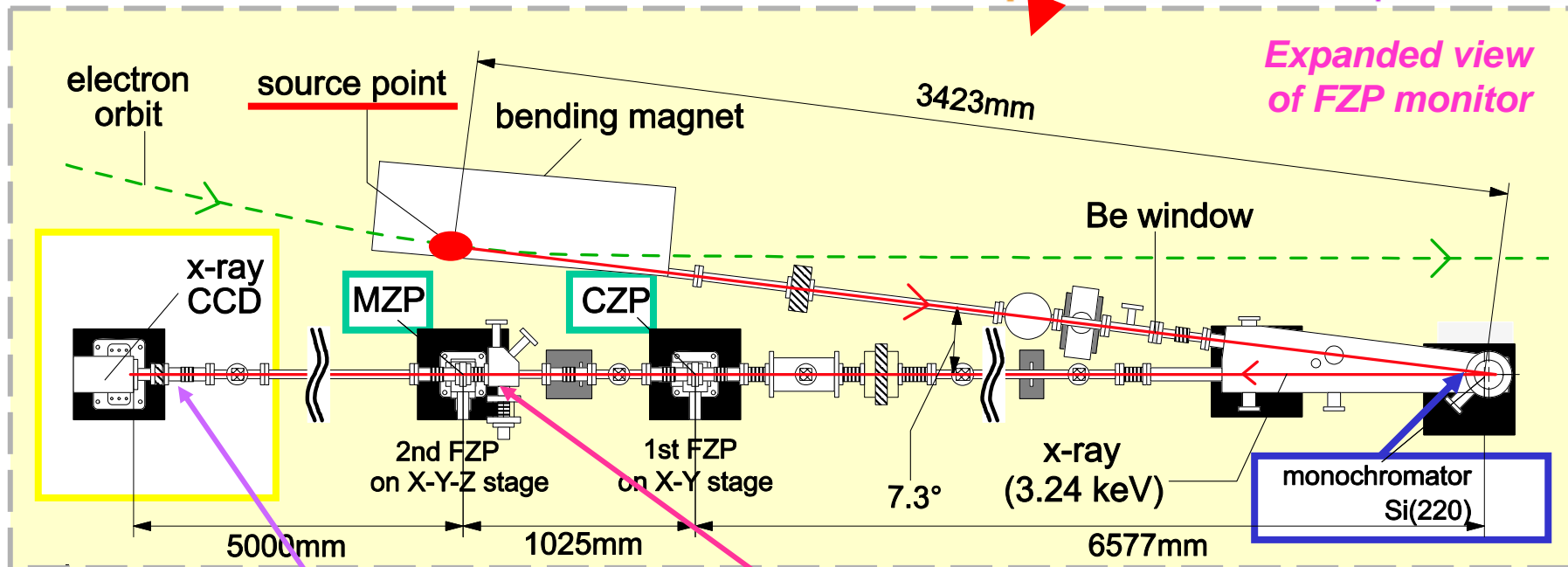
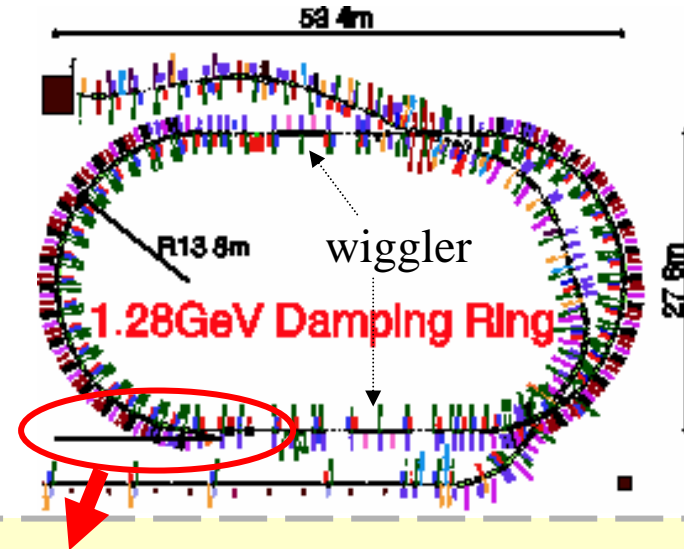
The total spatial resolution is **0.7 $\mu\text{m}$**  in R.M.S .



**Submicron** spatial resolution will be expected on this FZP monitor.

# Setup of FZP monitor

FZP monitor was installed at KEK-ATF damping ring.  
Expected beam sizes are  
**Horizontal: 50 $\mu\text{m}$ , Vertical: <10 $\mu\text{m}$**



*Expanded view of FZP monitor*

Previous shutter was set in front of CCD camera [shutter time >20ms]

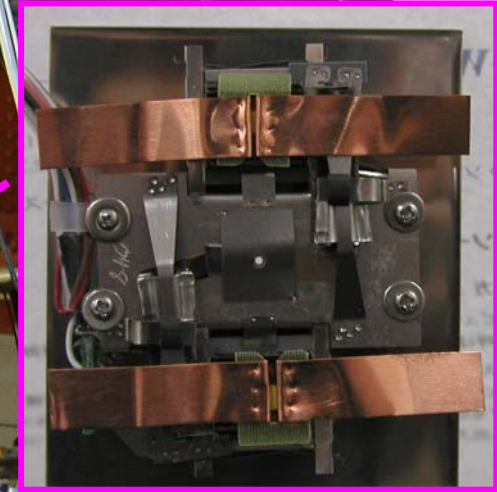
New mechanical shutter installed on April 2005 (opening shutter time <1ms)



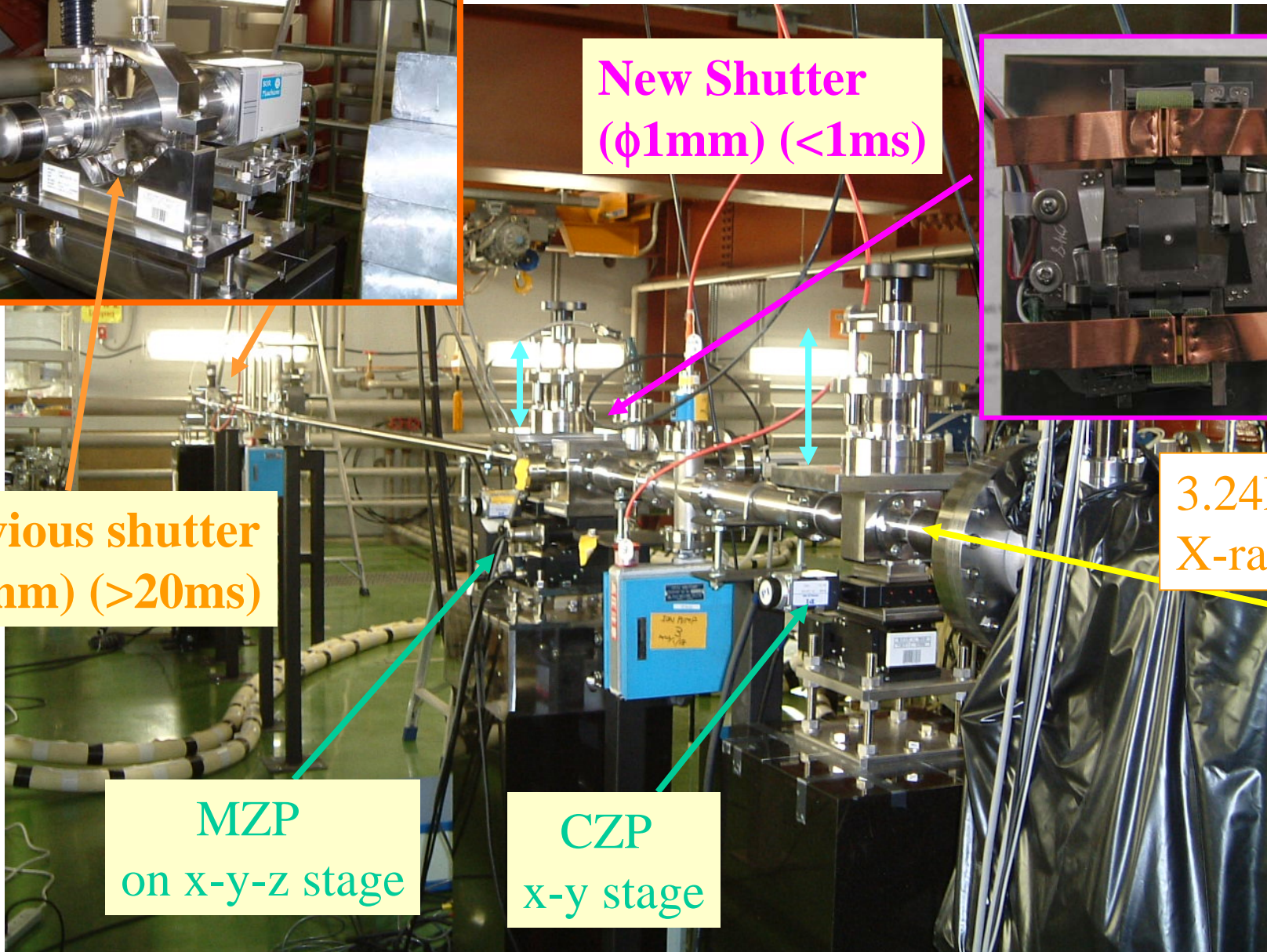
# Monitor Beam Line (picture)



New Shutter  
( $\phi 1\text{mm}$ ) ( $<1\text{ms}$ )



Previous shutter  
( $\phi 5\text{mm}$ ) ( $>20\text{ms}$ )

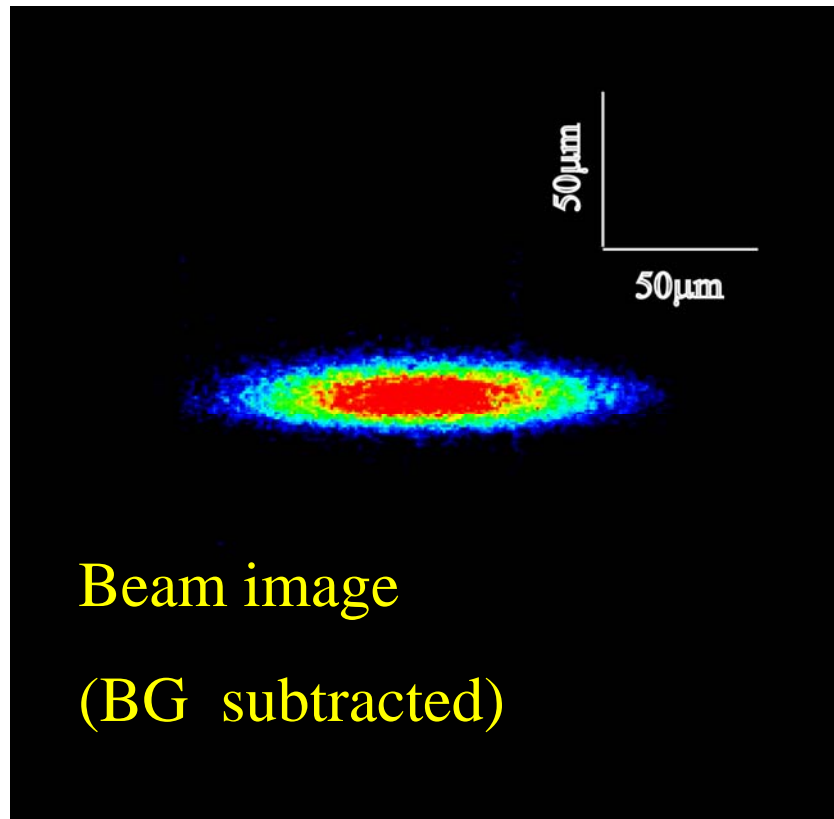


3.24keV  
X-ray

MZP  
on x-y-z stage

CZP  
x-y stage

# Example of beam image (shutter with 100ms)

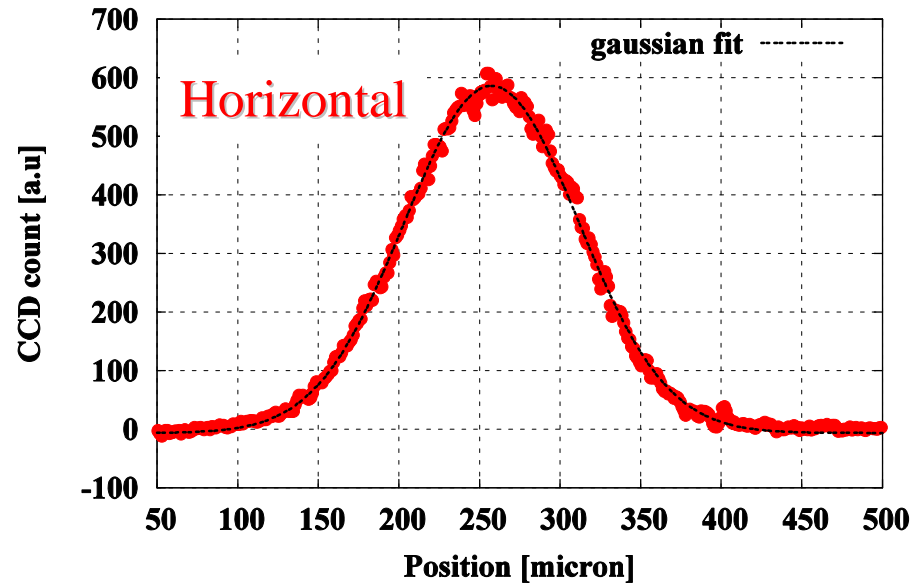


I=4.0mA, Shutter time = 100ms  
(2004/4/15)

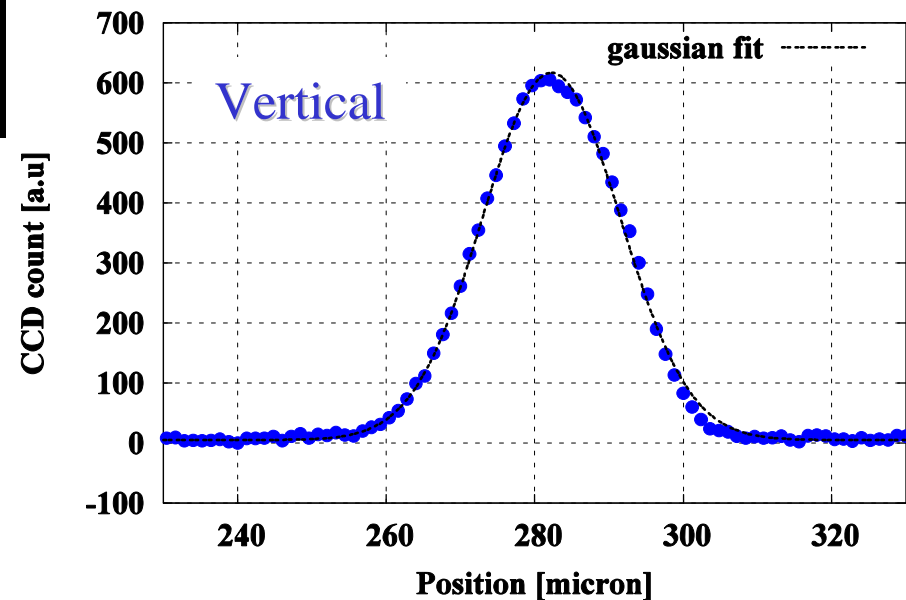
$$\sigma_x = 54.2 \pm 0.2 \text{ } [\mu\text{m}]$$

$$\sigma_y = 9.2 \pm 0.1 \text{ } [\mu\text{m}]$$

Horizontal beam size (2004/4/15, 4.0mA/1bunch)

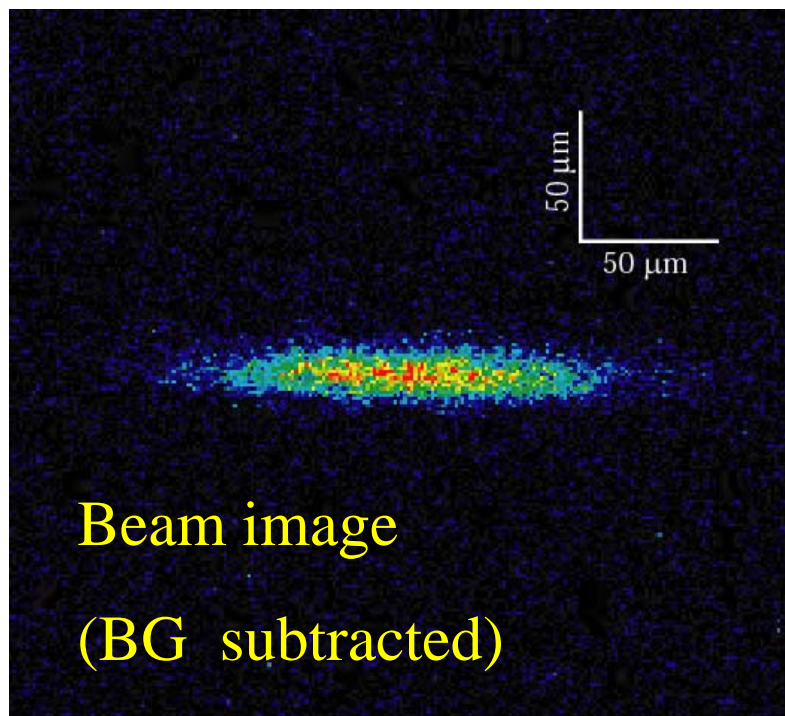


Vertical beam size (2004/4/15, 4.0mA/1bunch)





# Example of beam image (new shutter with 1ms)

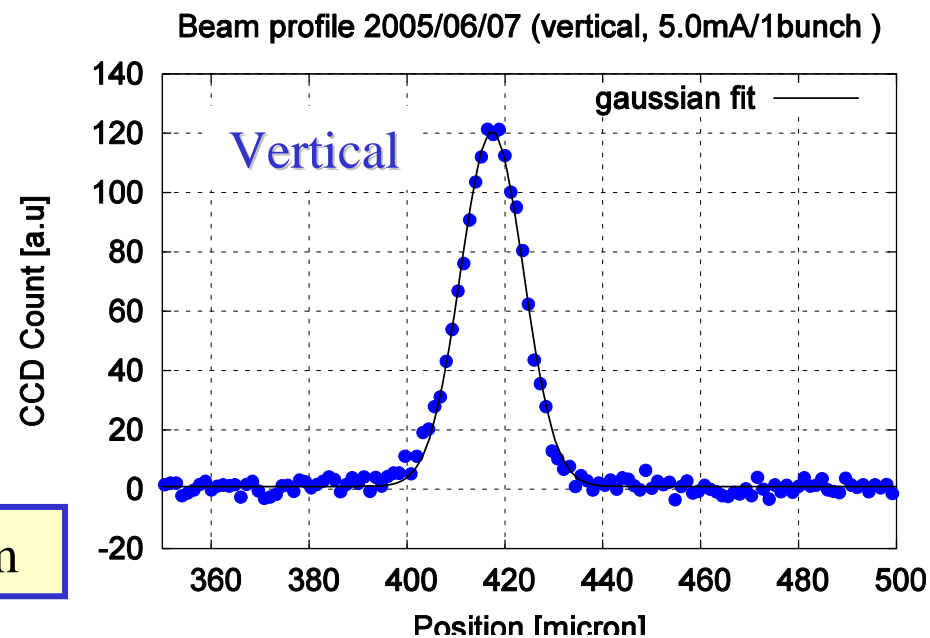
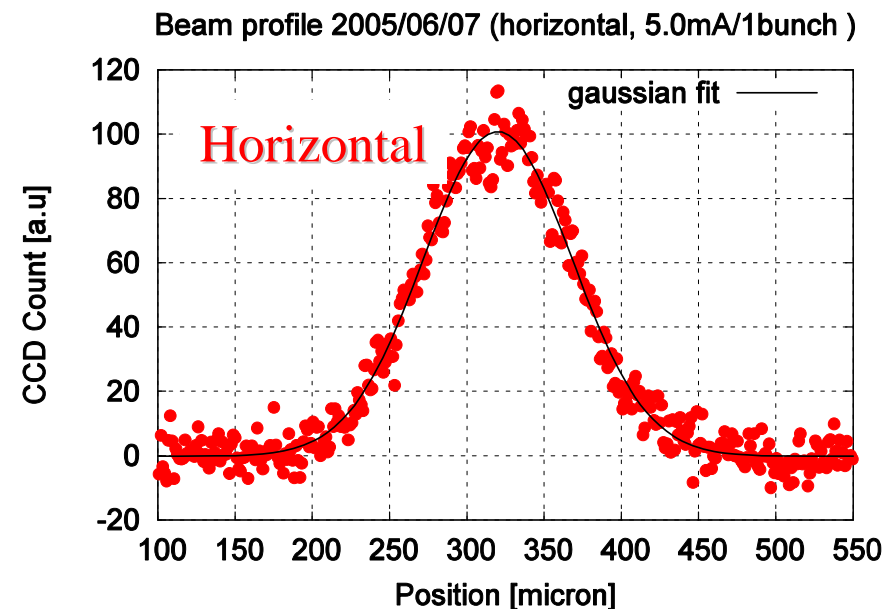


I=5.0mA, Shutter time = 1ms  
(2005/06/07)

$$\sigma_x = 48.2 \pm 0.5 \text{ } [\mu\text{m}]$$

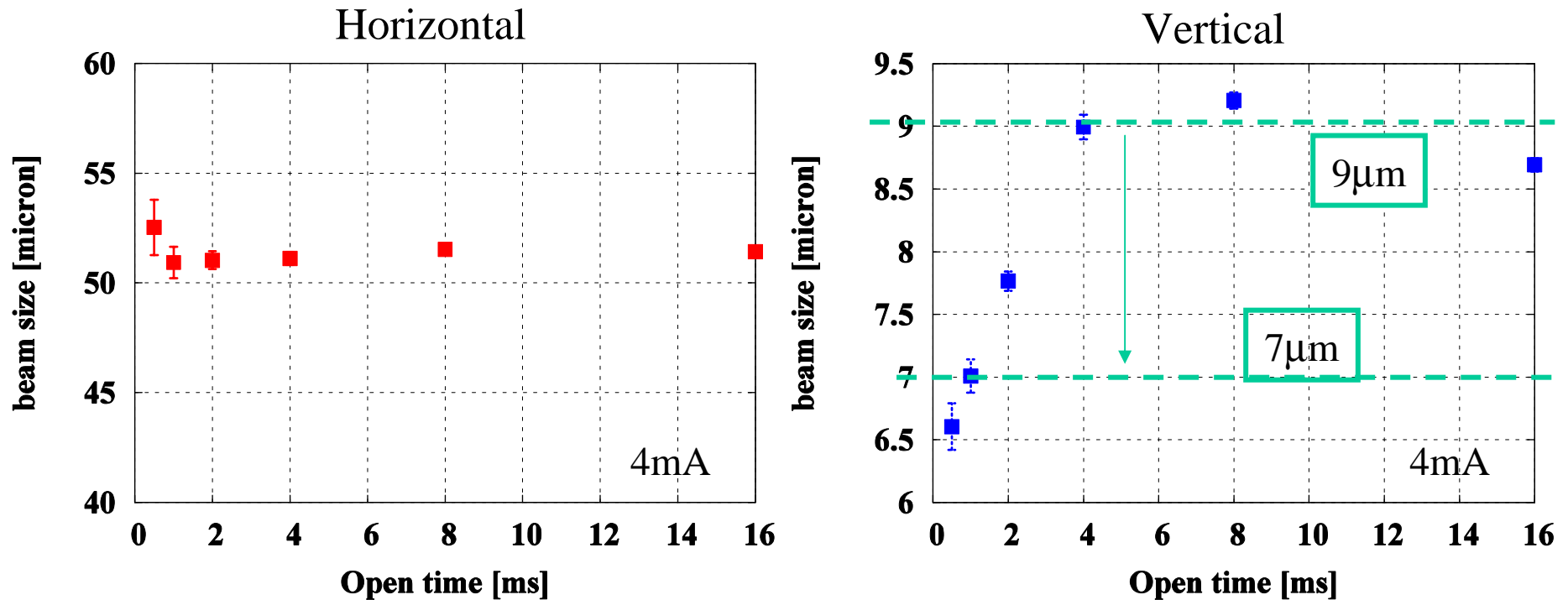
$$\sigma_y = 6.4 \pm 0.1 \text{ } [\mu\text{m}]$$

Reduce vertical beam size : 9.2μm → 6.4μm



# Shutter opening time dependence

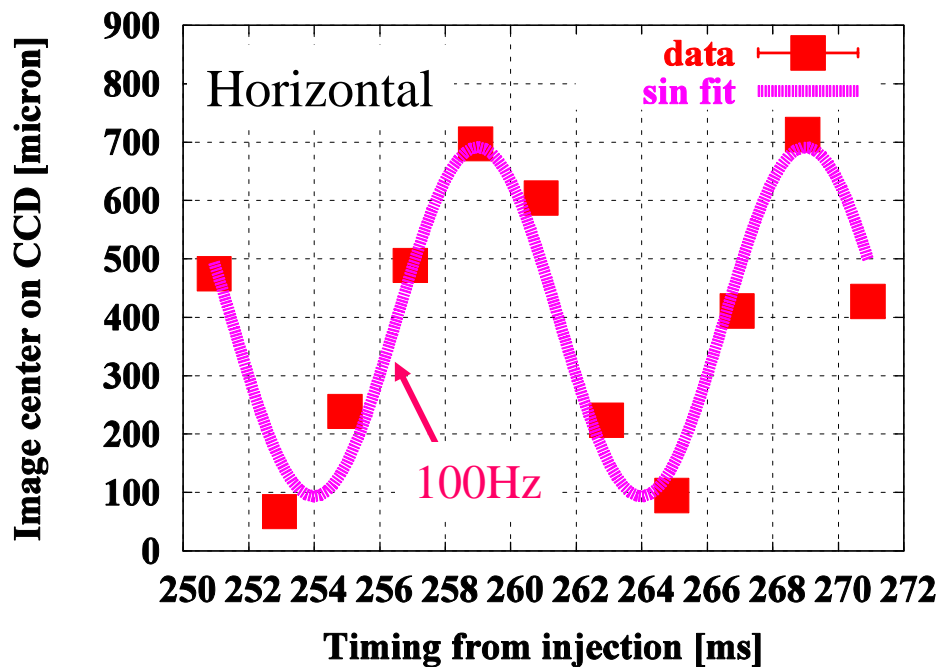
Measure the beam size by changing shutter opening time.



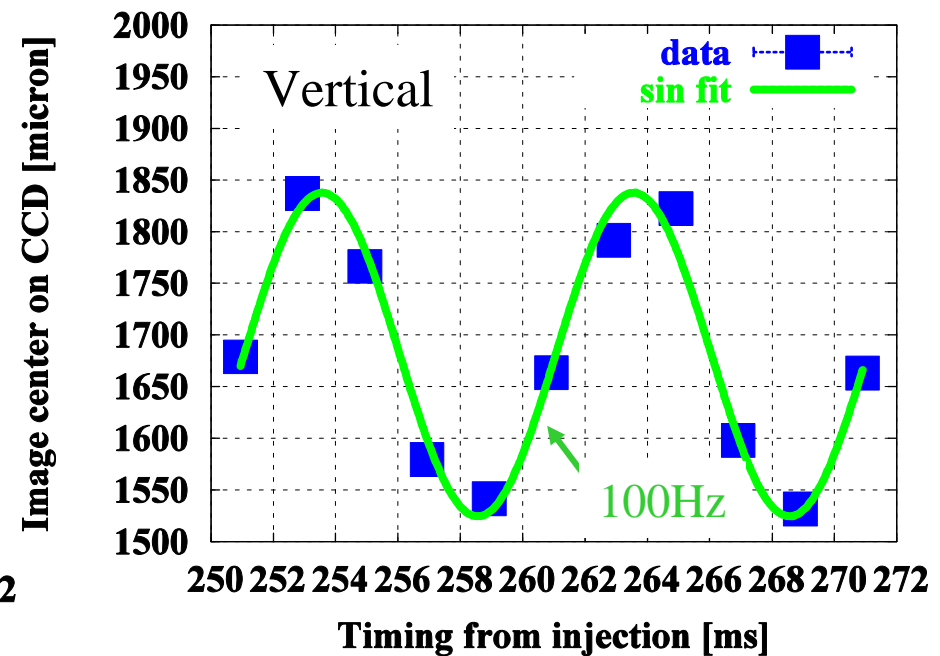
The measured horizontal beam size was almost 50 $\mu\text{m}$  and was independent of the shutter opening time. On the other hand, the measured vertical beam size was changed from 9 $\mu\text{m}$  to 7 $\mu\text{m}$  by changing the shutter opening time from 4ms shorter.

# Measurement of beam position oscillation

In order to search the enhancement of the vertical beam size, we measure the beam position by changing the shutter trigger timing from beam injection timing (shutter opening time fixed with 1ms.)



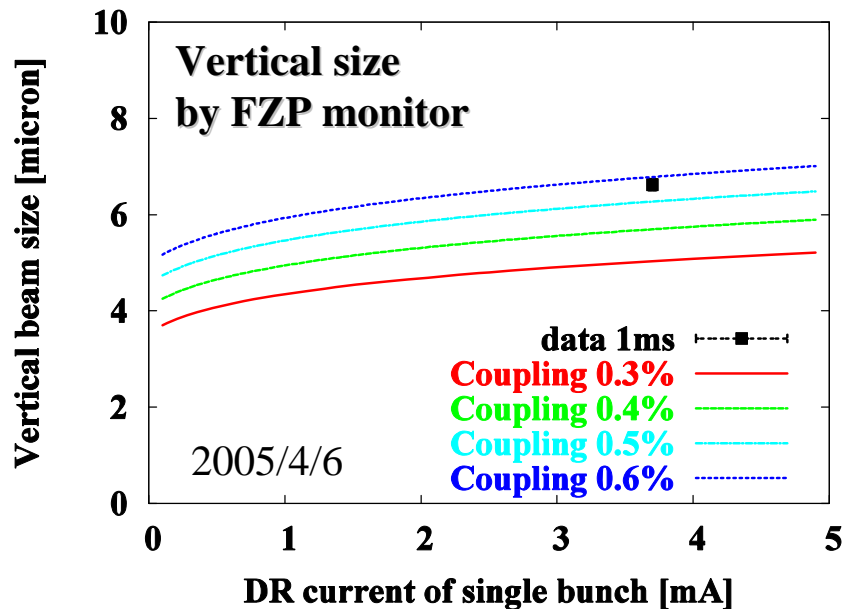
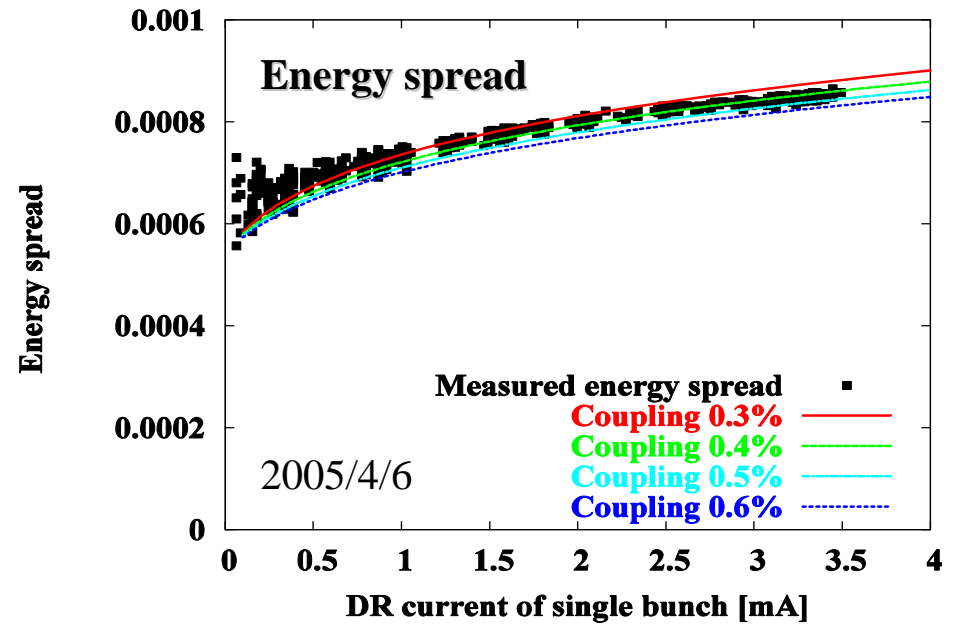
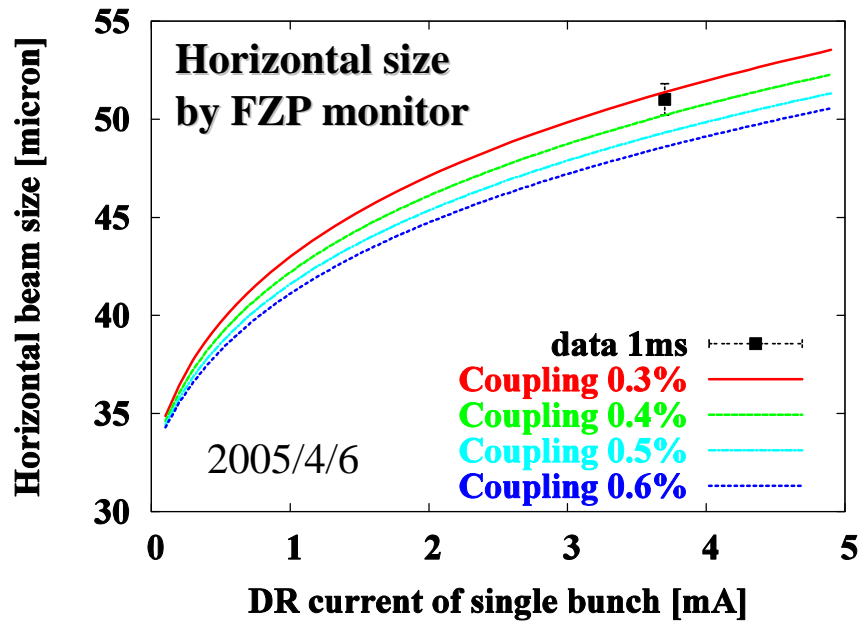
Horizontal amplitude :  $14.9\mu\text{m}$



Vertical amplitude :  $7.8\mu\text{m}$

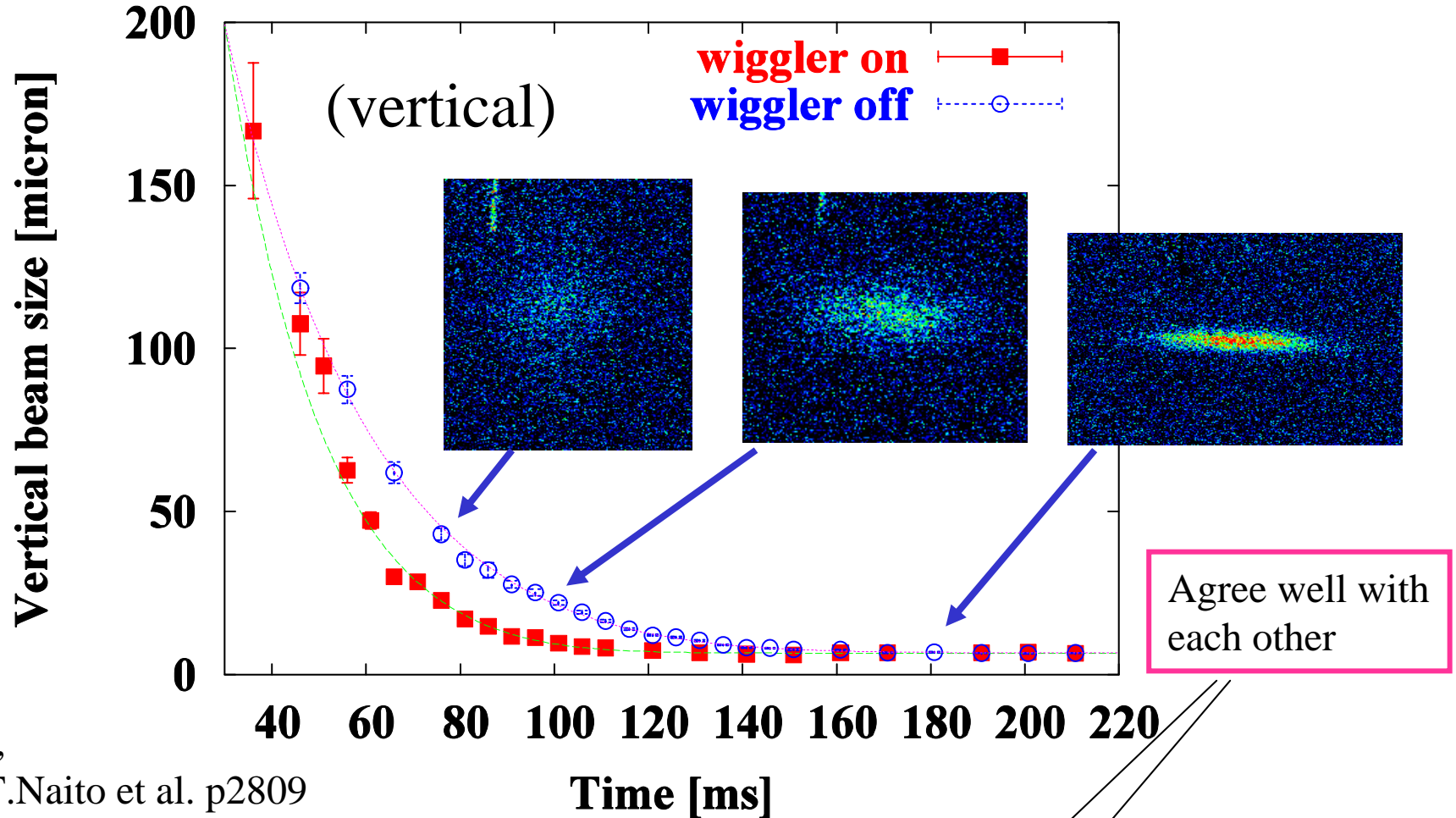
100Hz beam oscillation made the vertical beam size enhancement

# Measured sizes by FZP monitor vs calculation



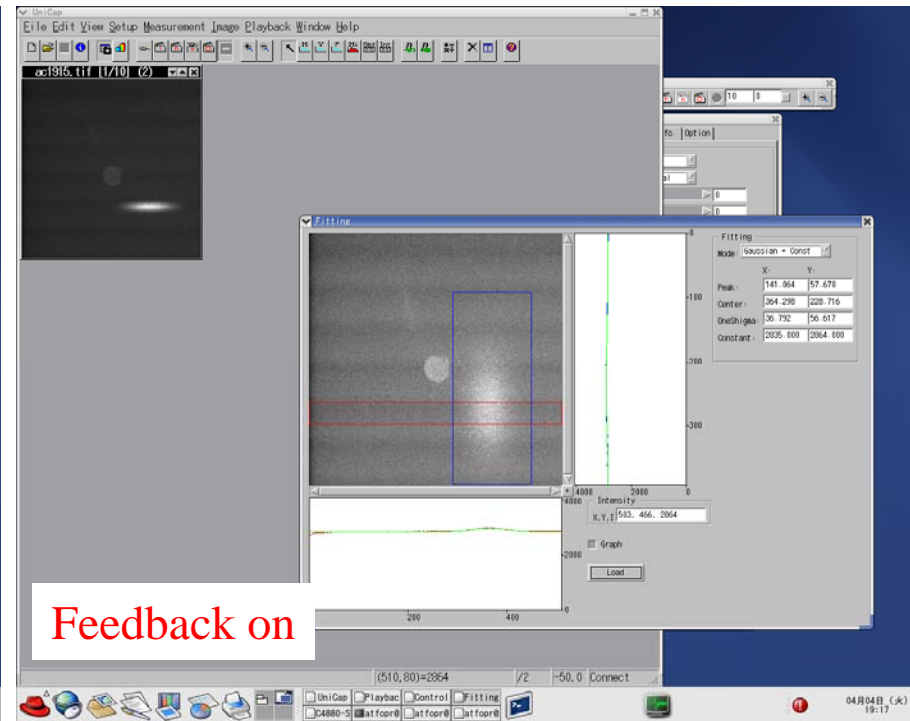
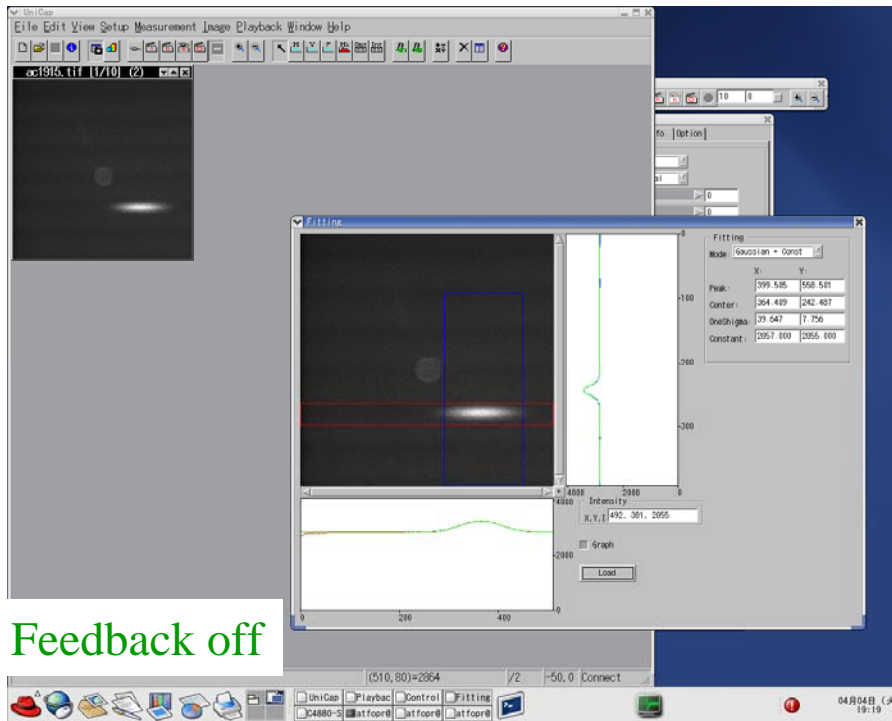
Three measurements (horizontal and vertical beam size by FZP monitor and energy spread by screen monitor at the extraction line plotted by black squares) agree well with the calculation results by assuming the betatron coupling of 0.3~0.6 % (solid and dotted lines)

# (Application) 1. Measurement of damping time



	Measurement of FZP monitor	Calculation
Wiggler off	$(30.9 \pm 0.6)$ ms	$(SAD)$ $28.5$ ms
Wiggler on	$(20.7 \pm 0.8)$ ms	21.1ms

## (Application) 2. Difference between Longitudinal feedback on and off (2006/4/4)



Horizontal : 47.6 $\mu\text{m}$   
Vertical : 9.3 $\mu\text{m}$

$$\sigma_x = \sqrt{\beta_x \epsilon_x + \left( \eta_x \frac{\sigma_p}{p} \right)^2}$$

Horizontal : 44.2 $\mu\text{m}$   
Vertical : 67.9 $\mu\text{m}$

Live mode: no BG subtract TTL pulse 20ms (※ Don't remove the effect of 100Hz oscillation)

The large vertical beam profile enhancement was observed by adding longitudinal feedback on. This data is consistent with the measurement of wire scanner at extraction line. (The reason was not understood. Please ask Naito-san)

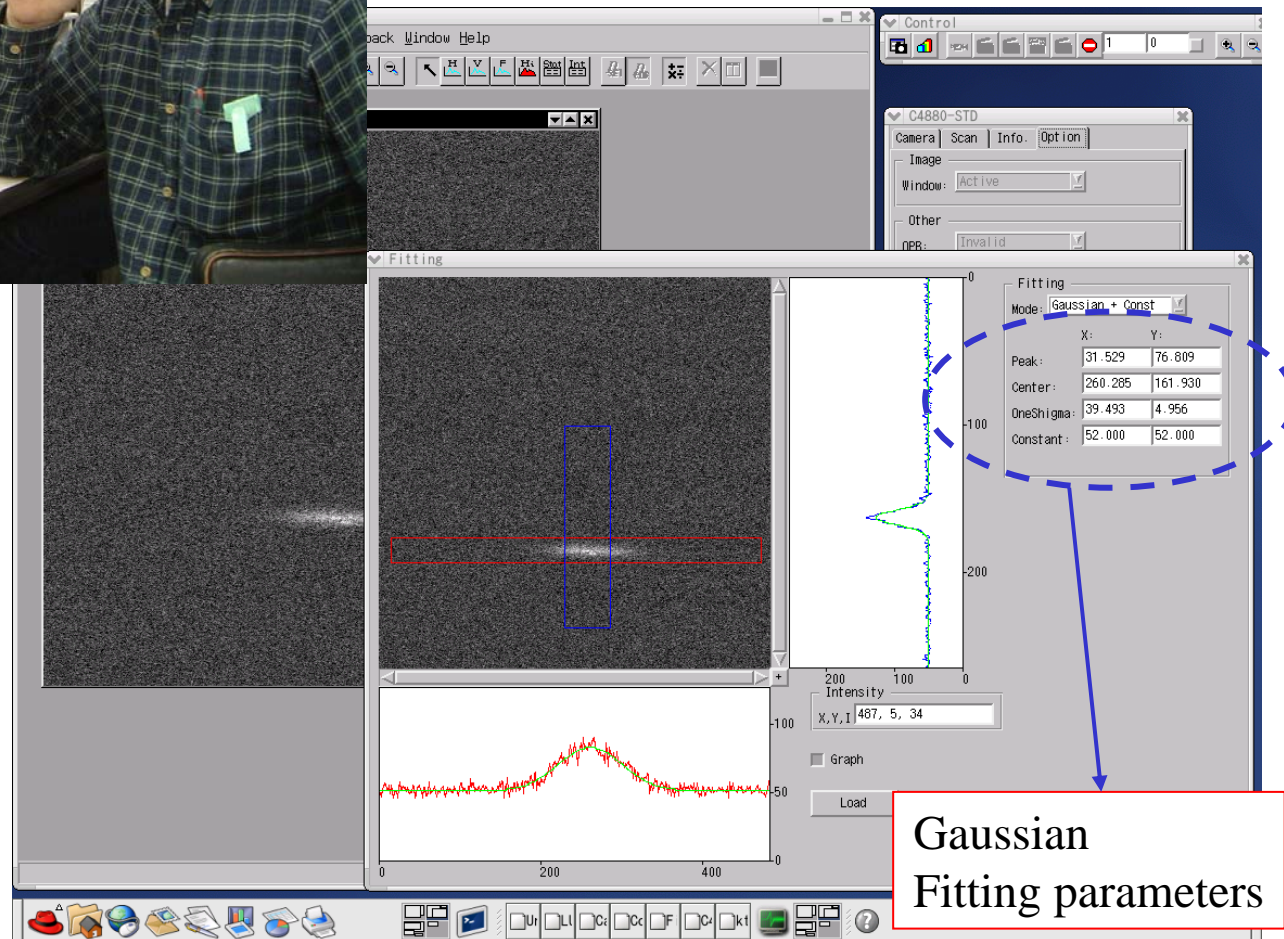


# Remote data taking of FZP monitor



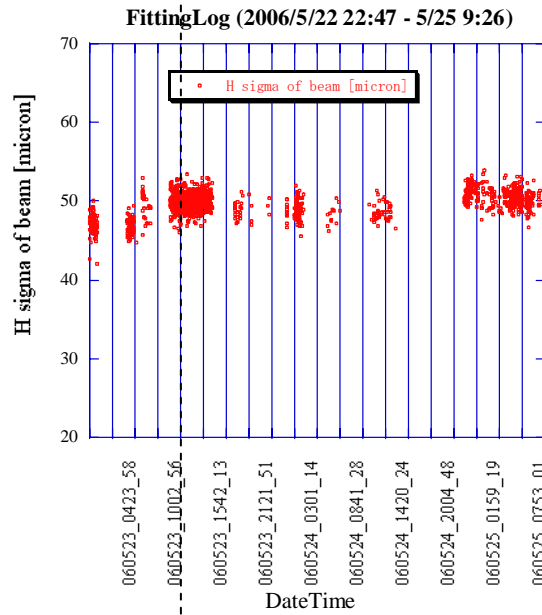
Monitor panel was set on  
the ATF 1<sup>st</sup> container.

Now we can  
continuously take  
data of FZP monitor  
on ATF 1<sup>st</sup> container  
from April 2006.

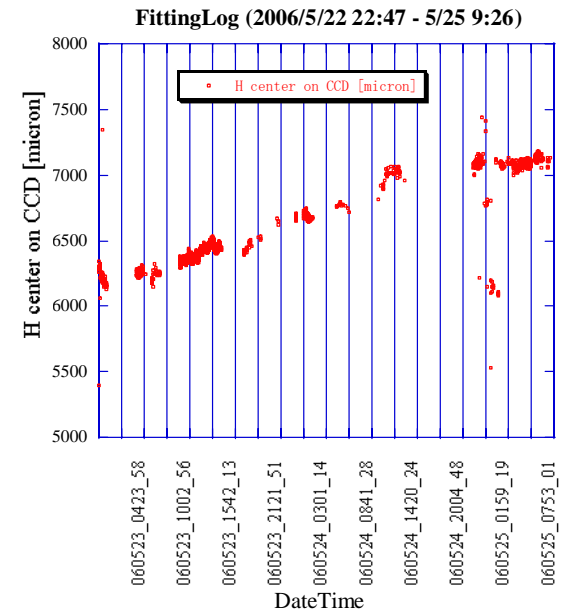


# Longterm position & size (2006/5/22 – 5/25)

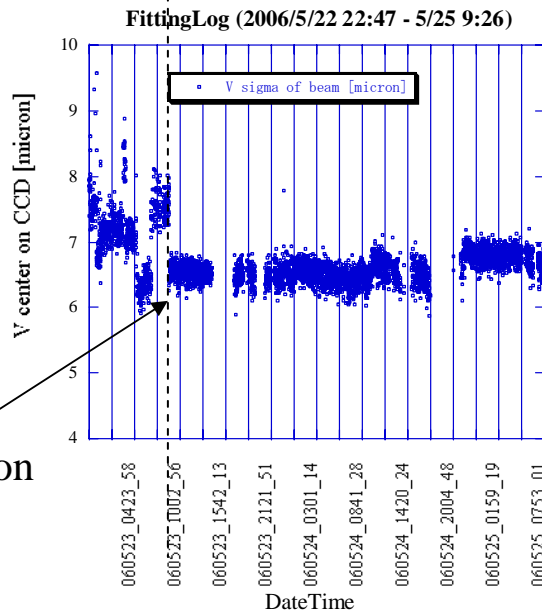
Horizontal size



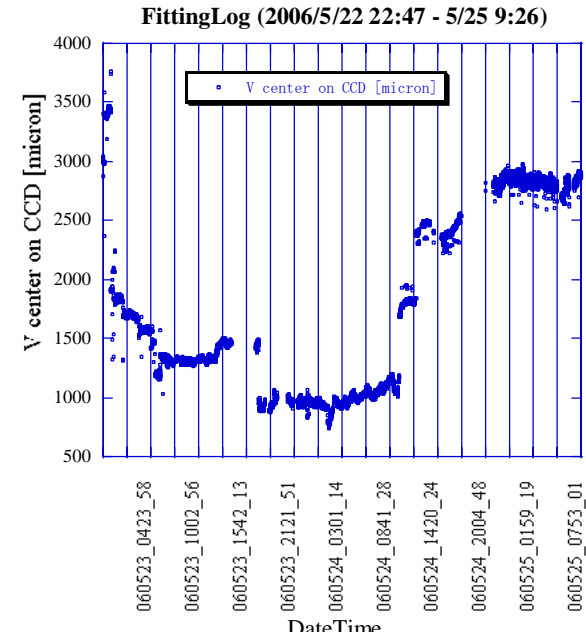
Horizontal position



Vertical size



Vertical position



Skew correction was done

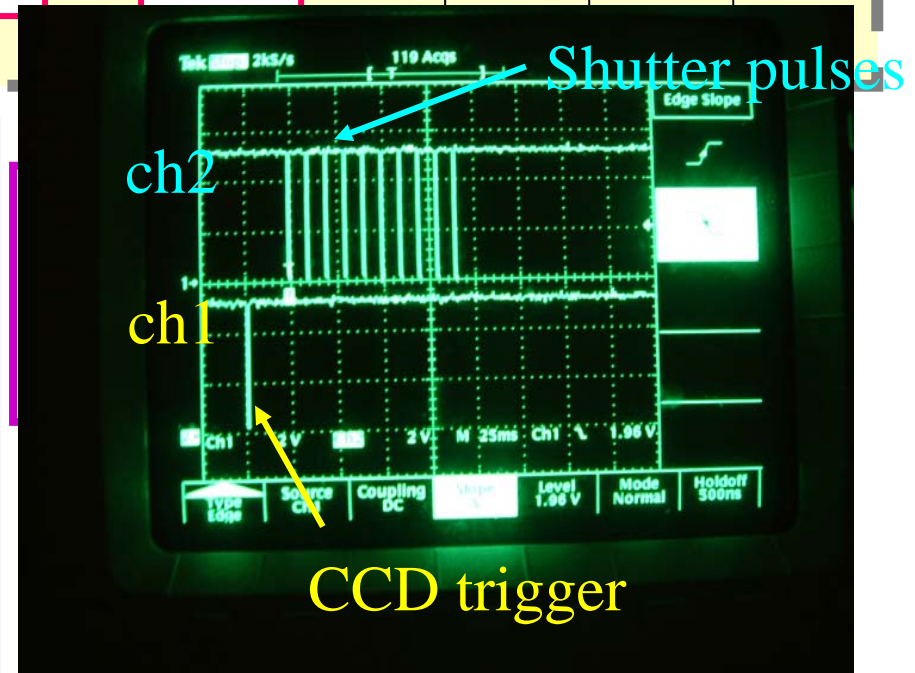
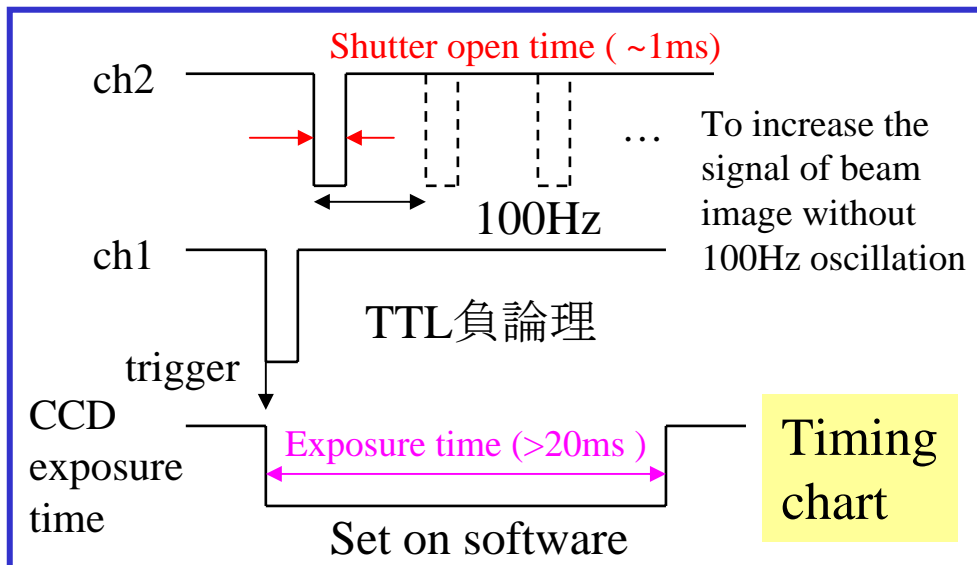
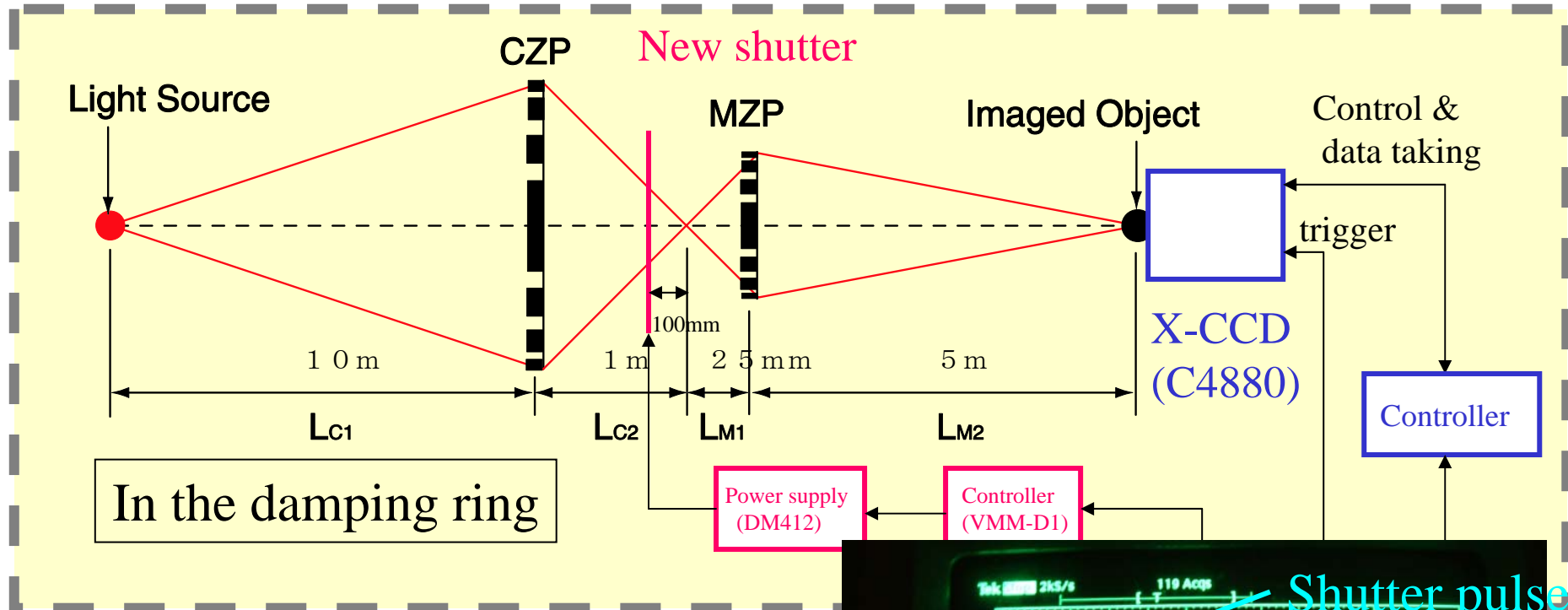
# Summary & Future

- We measure the beam size by using FZP monitor at KEK-ATF damping ring. The effect of the unknown 100Hz oscillation was removed on the measurement by using new mechanical shutter with 1ms shutter opening time. After that, the measured vertical beam size of this monitor was less than  $7\mu\text{m}$ .
- The measured horizontal and vertical beam sizes by FZP monitor and the measured energy spread agreed well with the calculation by assuming the coupling ratio with  $0.3\sim 0.6\%$  with including intra beam scattering .
- The damping time of ATF damping ring with/wihout wiggler were clearly measured by using FZP monitor. The measured damping time agrees well with calculation with each other.
- We can use the FZP monitor as online monitor.

# Future plan

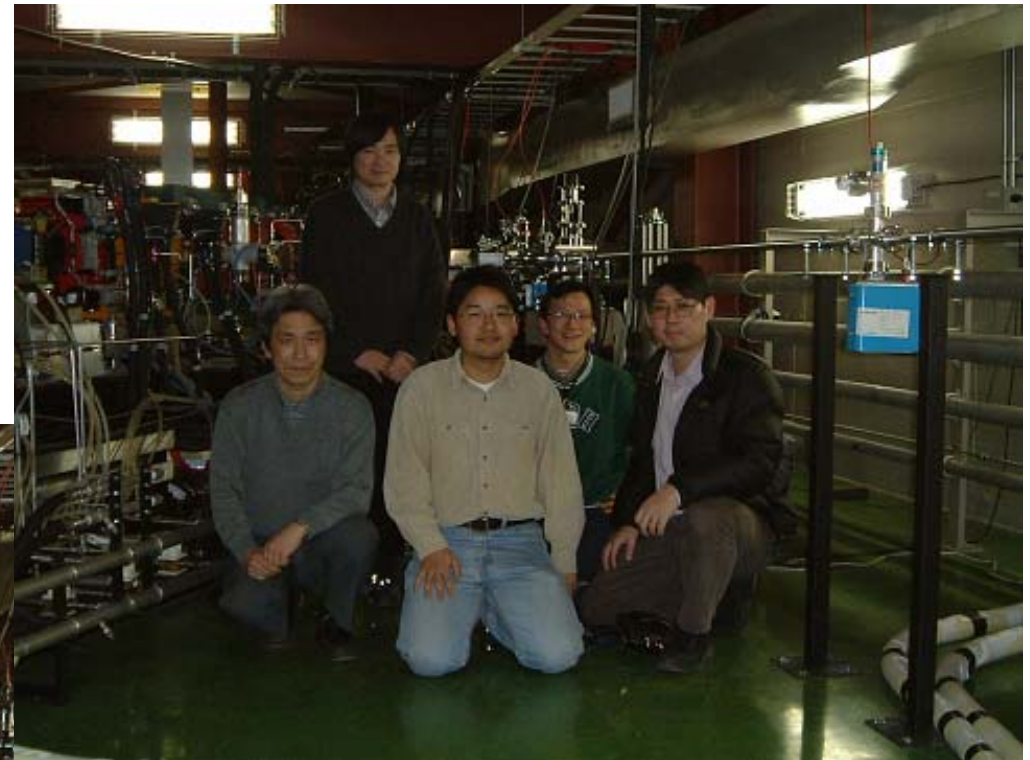
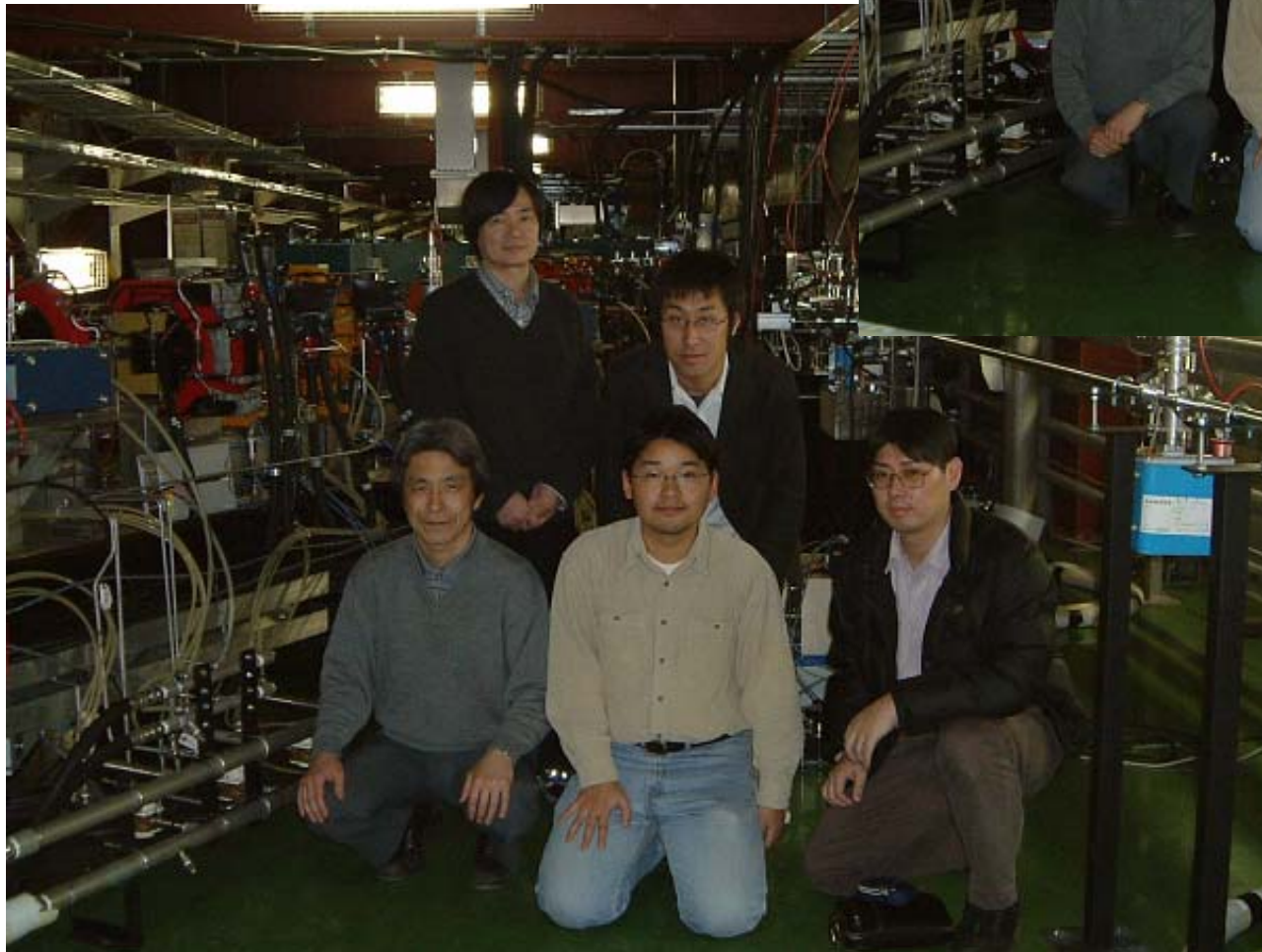
- Search the 100Hz vibration source
  - Measure the correlation with B,Q,S power supply data and/or temperature.
  - Plan to add new digital BPM system (Libera) less than  $1\mu\text{m}$  resolution near FZP monitor
- Increase the S/N ratio.
  - apply multi pulses operation (now under going)
- Longterm stability
  - We need to data taking correlated with DCCT ,BPM and other monitor on same data

# Multi pulses operation





Thank you



Welcome Kuriki-san  
(KEK) and Itoh-san  
(ISSP U-tokyo) to new  
FZPmonitor group  
from April 2006.





# References

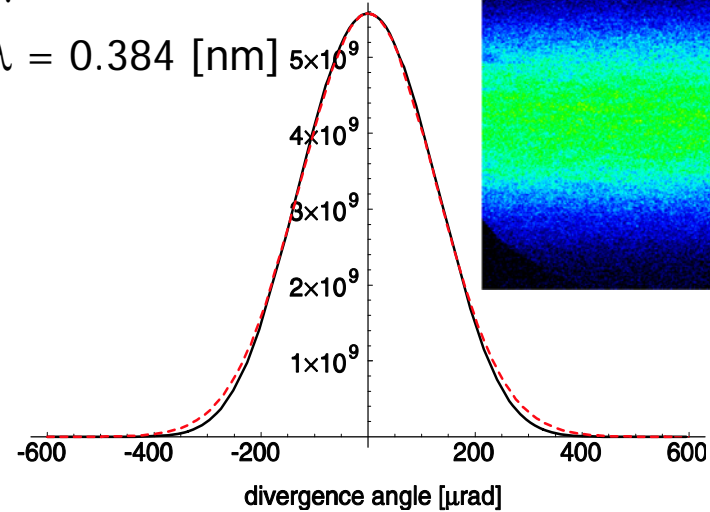
# Photon Flux

Energy  $E=1.28$  [GeV]  
 Bending field  $B=0.748$  [T]  
 Critical length  $\lambda_c = 1.52$  [nm]

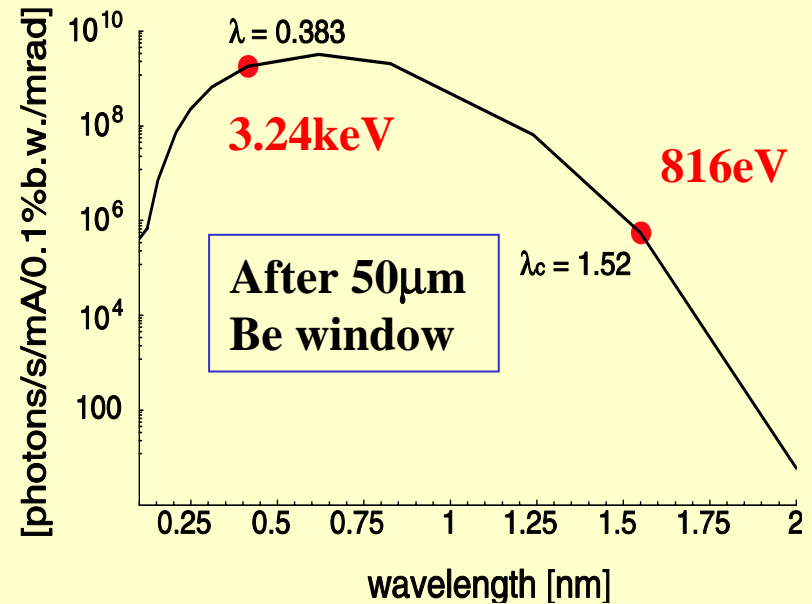
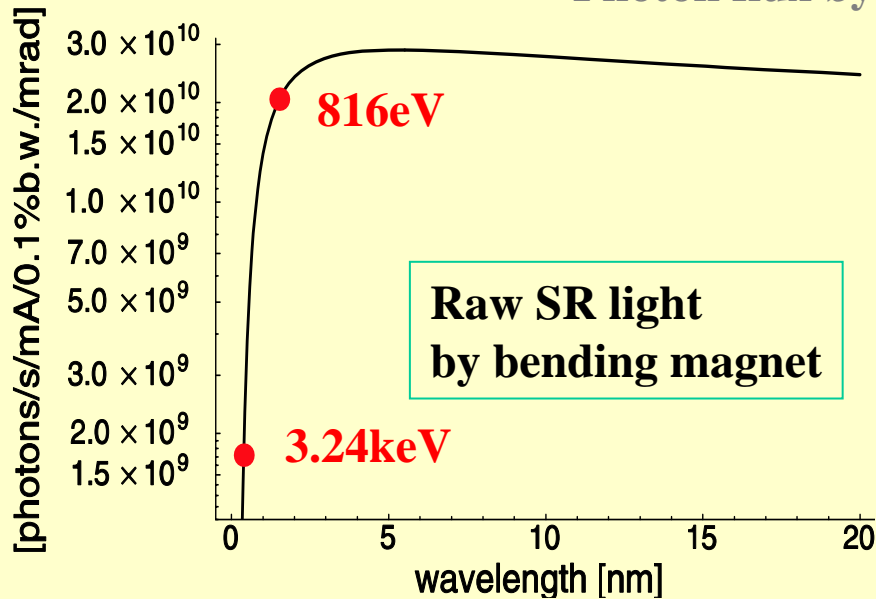
$$\sigma_{SR} [\text{mrad}] = 0.289 \left( \frac{\lambda}{\lambda_c} \right)^{0.425} / E [\text{GeV}]$$

$\sigma_{SR} = 126$   
 [ $\mu\text{rad}$ ]

$\lambda = 0.384$  [nm]



Photon flux by SR source point

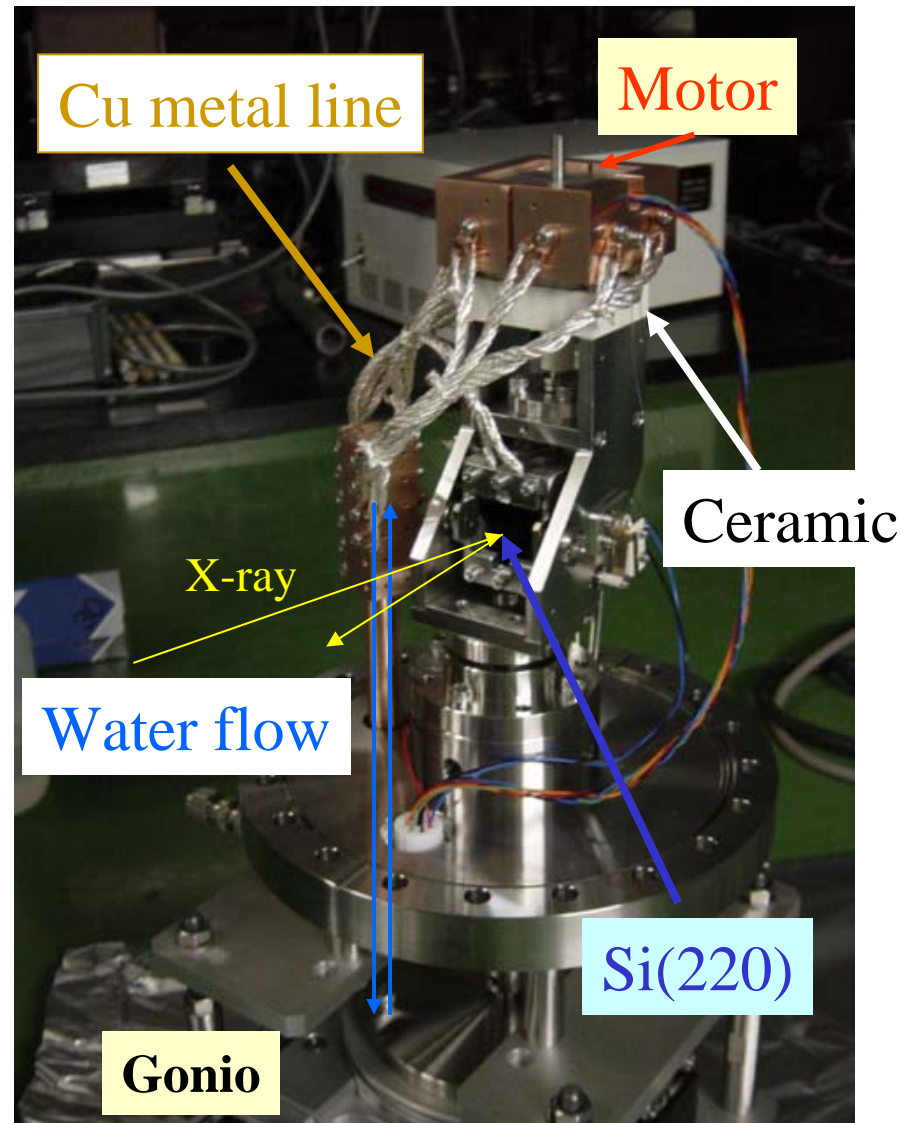


# Monochromator

Crystal	Si (220)
Grid interval	$d = 0.192$ [nm]
Bragg angle	$\theta_B = 86.35$ deg
Wave length	$\lambda = d \sin\theta_B$ $= 0.383$ [nm]
Energy resolution	$\frac{\Delta\lambda}{\lambda} = 5.6 \times 10^{-5}$

Enough energy resolution for avoiding chromatic aberration of FZP ( $8 \times 10^{-4}$ )

Mirror angle drift is reduced less than **a few  $\mu$ rad** by adding the **water cooling**



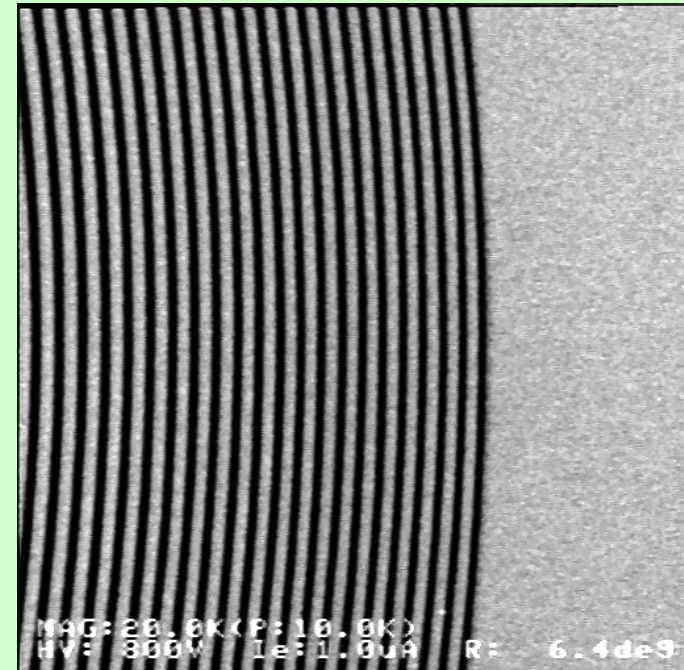
# Fresnel Zone Plates

Parameters of two FZP ( $\lambda = 0.383 \text{ nm}$ )

FZP resolution defined by  $\varrho^{\text{ESB}} = 1.55 \sqrt{\lambda}$

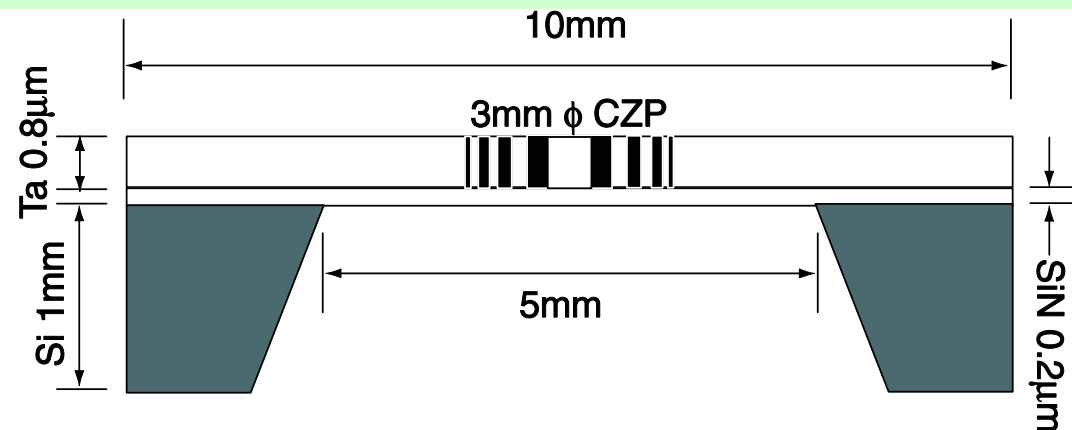
	CZP	MZP
Number of Zone	6444	146
Radius	1500 $\mu\text{m}$	37.3 $\mu\text{m}$
Most outer zone width $\Delta r_N$ ( $\delta_{\text{FZP}}$ )	116nm (142nm)	128nm (156nm)
Focal length f	909mm	24.9mm
Magnification	1/10	200

Outer zone of MZP by SEM



Cross Section of FZP

Produced by  
NTT-AT corp.



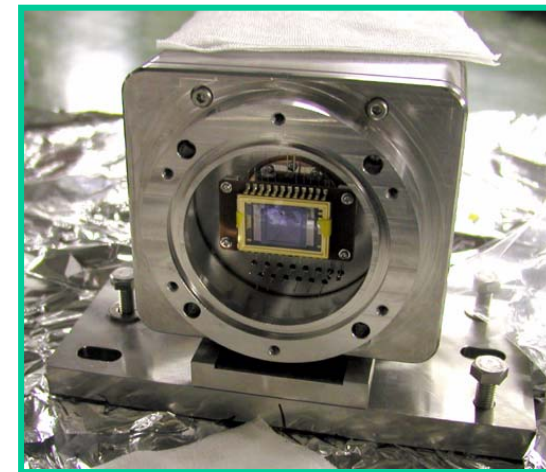
# X-ray CCD

CCD	Backward full frame transfer type
Area	12.29 mm x 12.29 mm
Pixel size	24 $\mu\text{m}$ x 24 $\mu\text{m}$
Quantum efficiency	< 90 % (3.24 keV)
Cooling	Peltier (-50 C°)
Dark current	2 electrons/pixels/sec
Scanning speed	7 frame/sec (Live) 0.5 frame/sec
Shutter speed	(Acquire) Less than 20ms

C4880-21-24-WD

(made by Hamamatsu K.K)

X-ray shutter



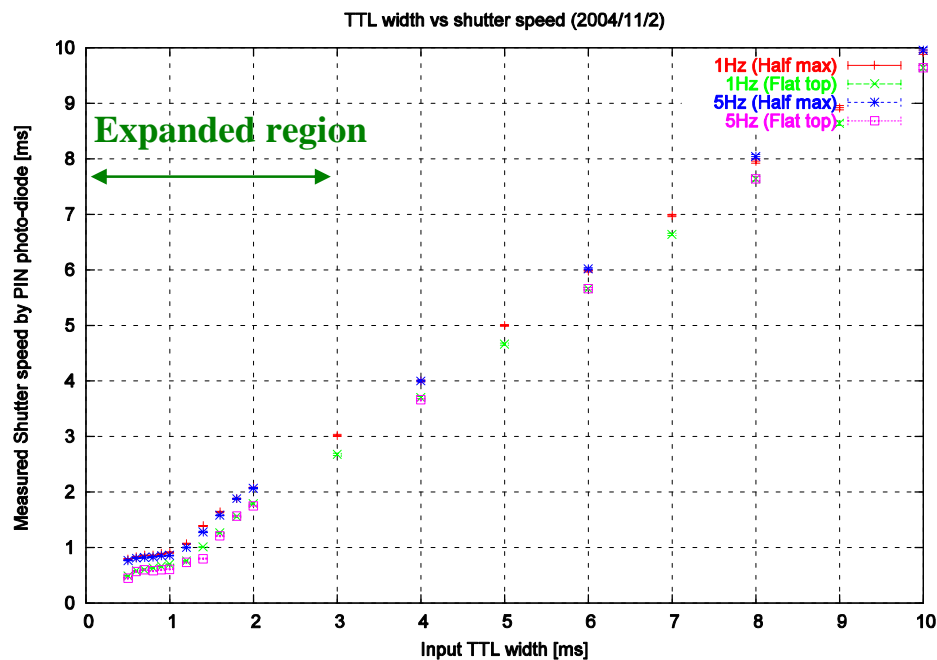


# Performance (Normal mode) at test bench

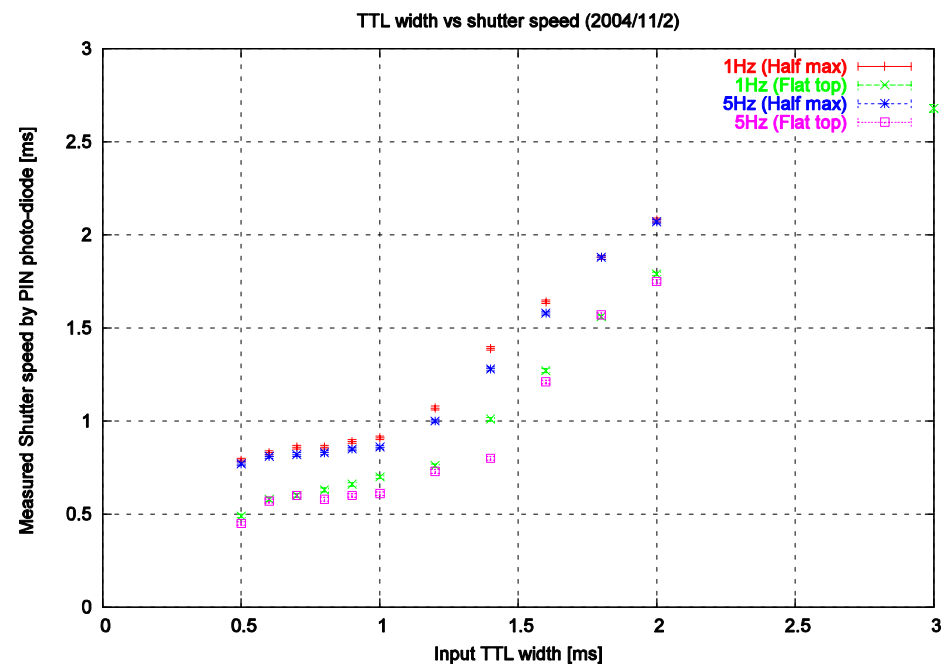
Horizontal : width of input TTL pulse

Vertical : measured shutter width by using laser and PIN photo diode

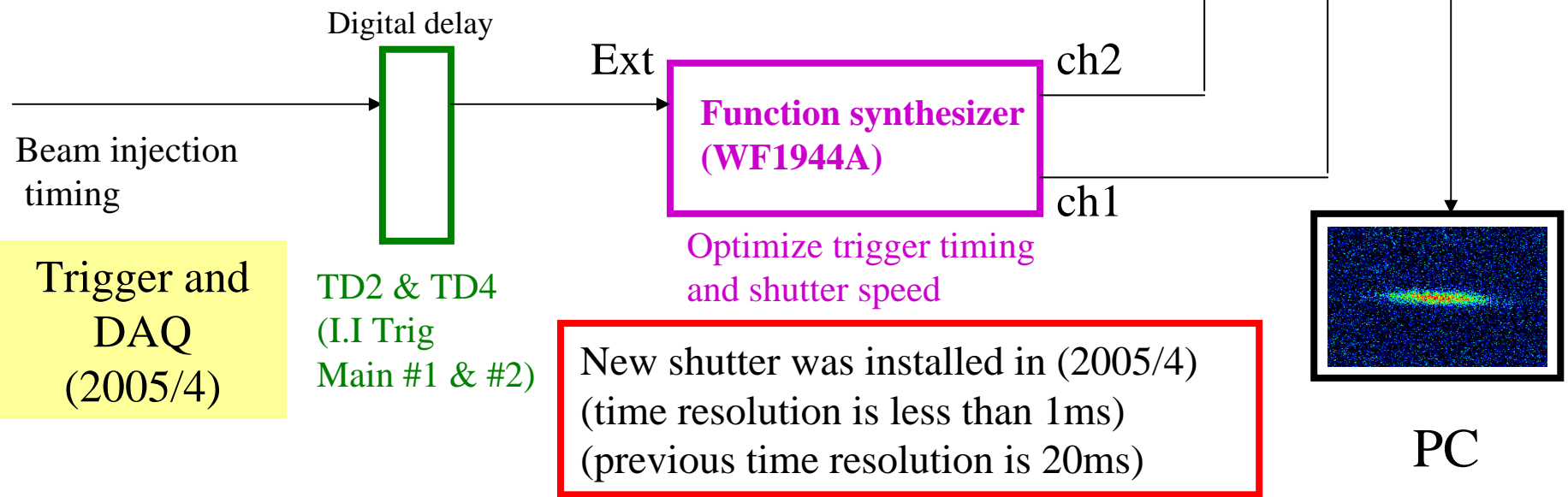
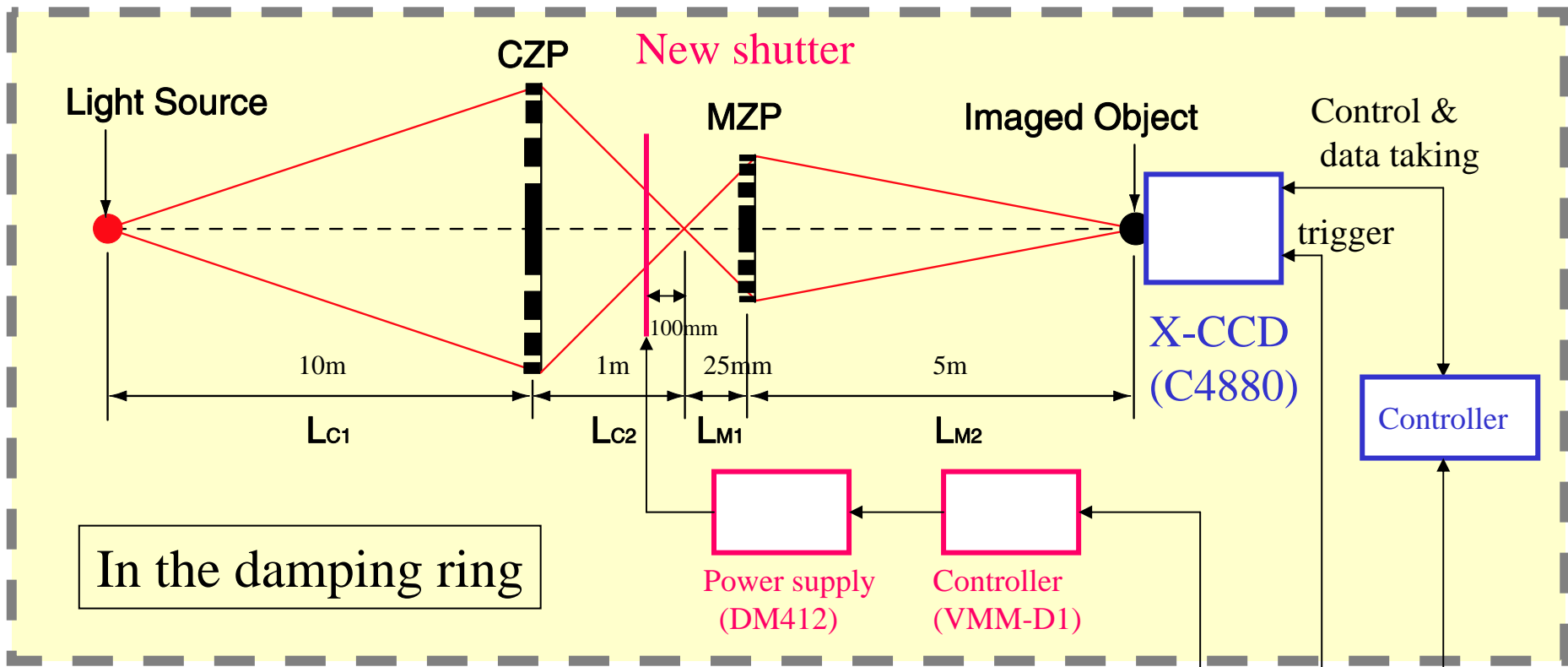
All view



Expanded view

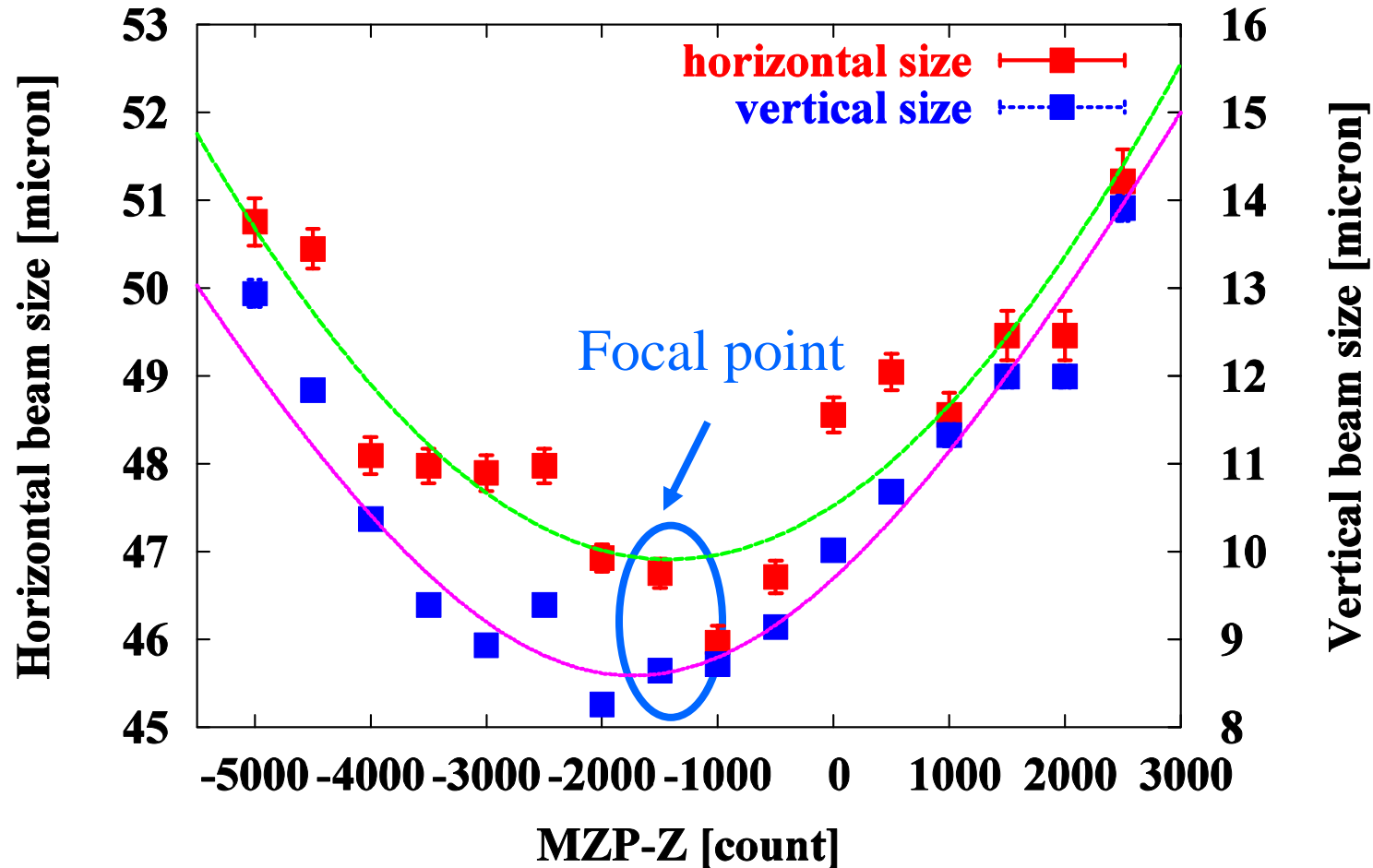


Minimum width of shutter opening time is less than 1ms



# MZP z-scan

MZP\_Z scan 2004/04/07 (2.0mA/1bunch)

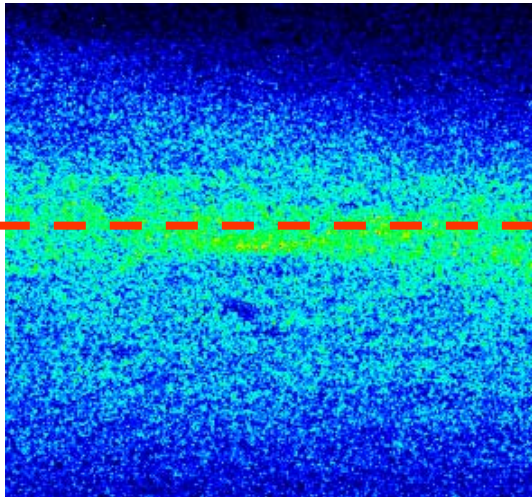


Find the focal point on X-CCD by moving MZP longitudinally.

# Alignment strategy

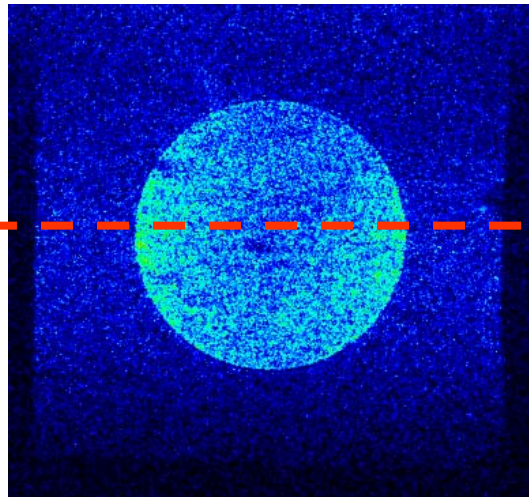
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1



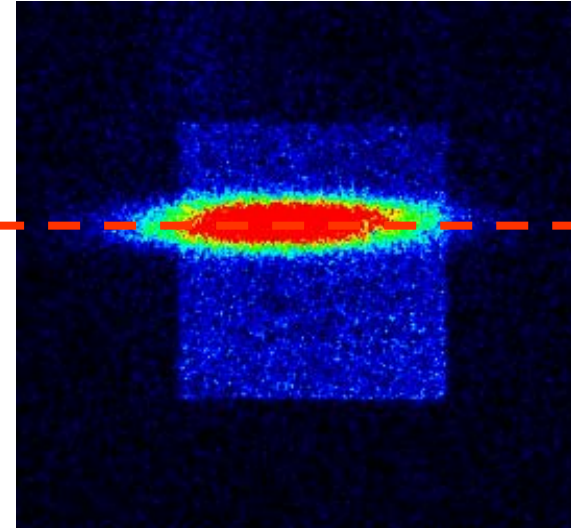
See direct SR light

2



Enter the CZP

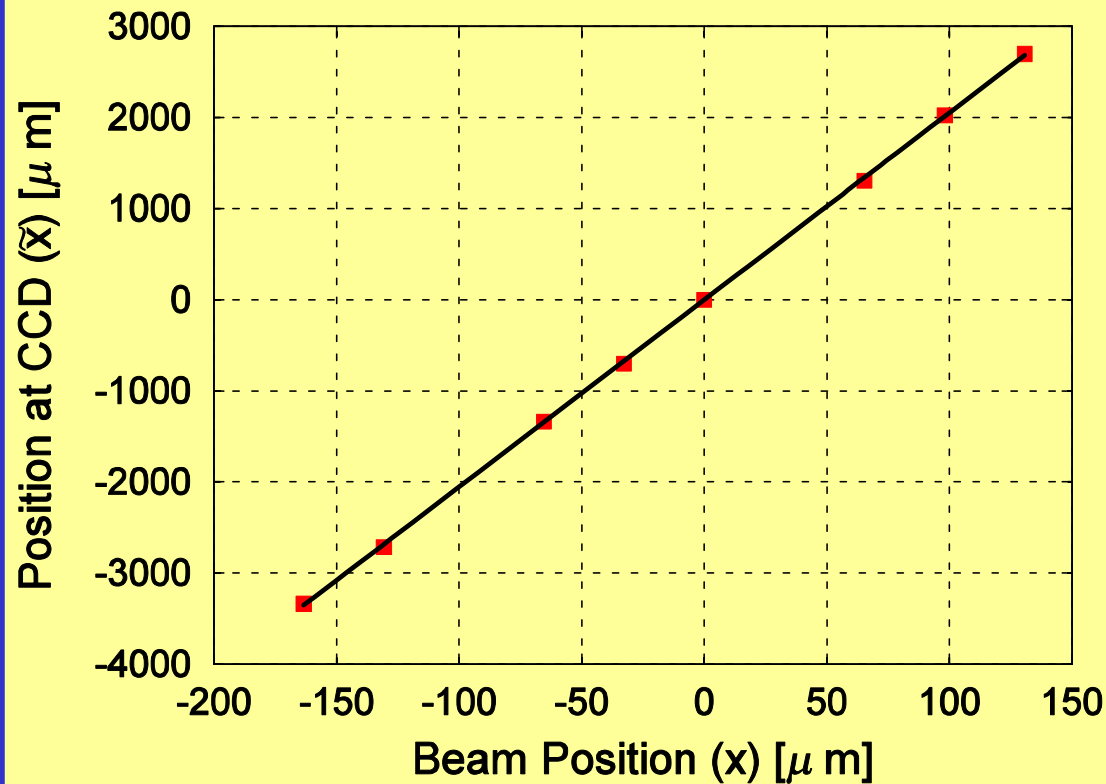
3



Enter the MZP

All of the image centers were adjusted on SR light center.

# Measurement of magnification



$$\Delta\tilde{x} = M\Delta x = -M \frac{\eta_x}{\alpha_M} \frac{\Delta f}{f_{\text{RF}}}$$

$$\alpha_M = 0.002134$$

$$f_{\text{RF}} = 714 \text{ [MHz]}$$

$$\eta_x = 0.04980$$

$$\pm 0.0018 \text{ [m]}$$

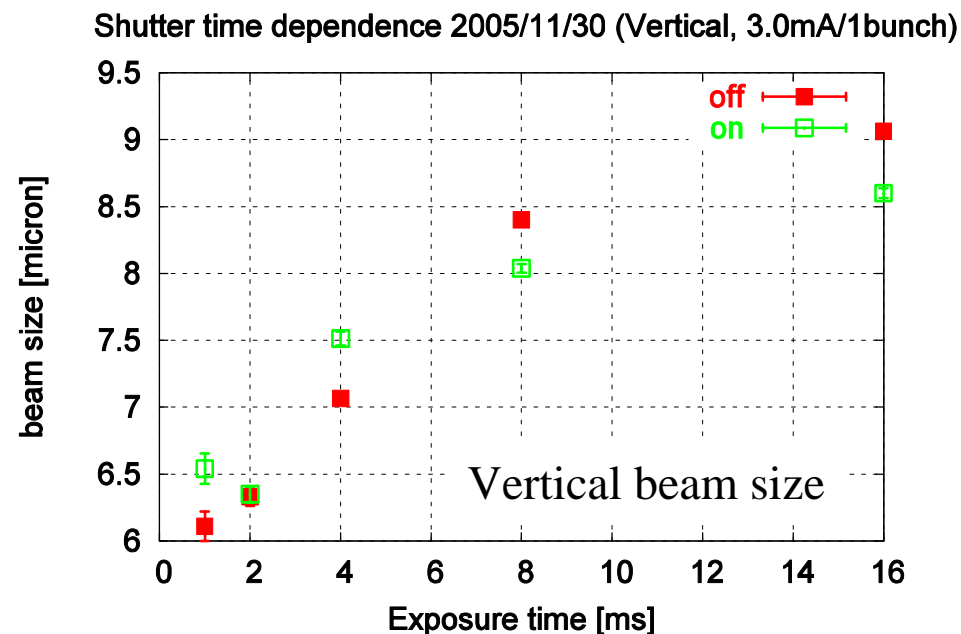
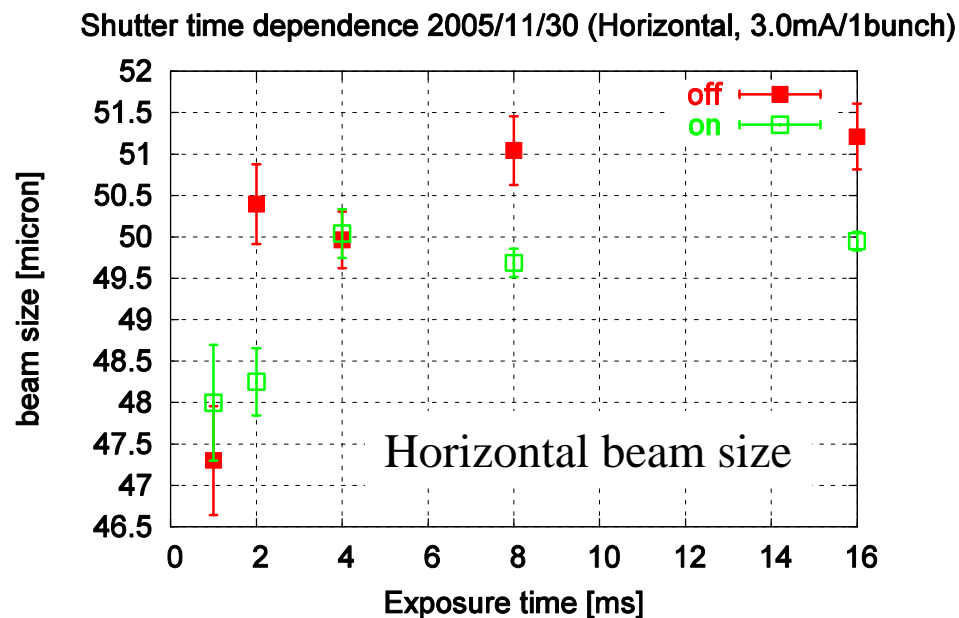
$$M = 20.53 \pm 0.76$$

Consistent with design value

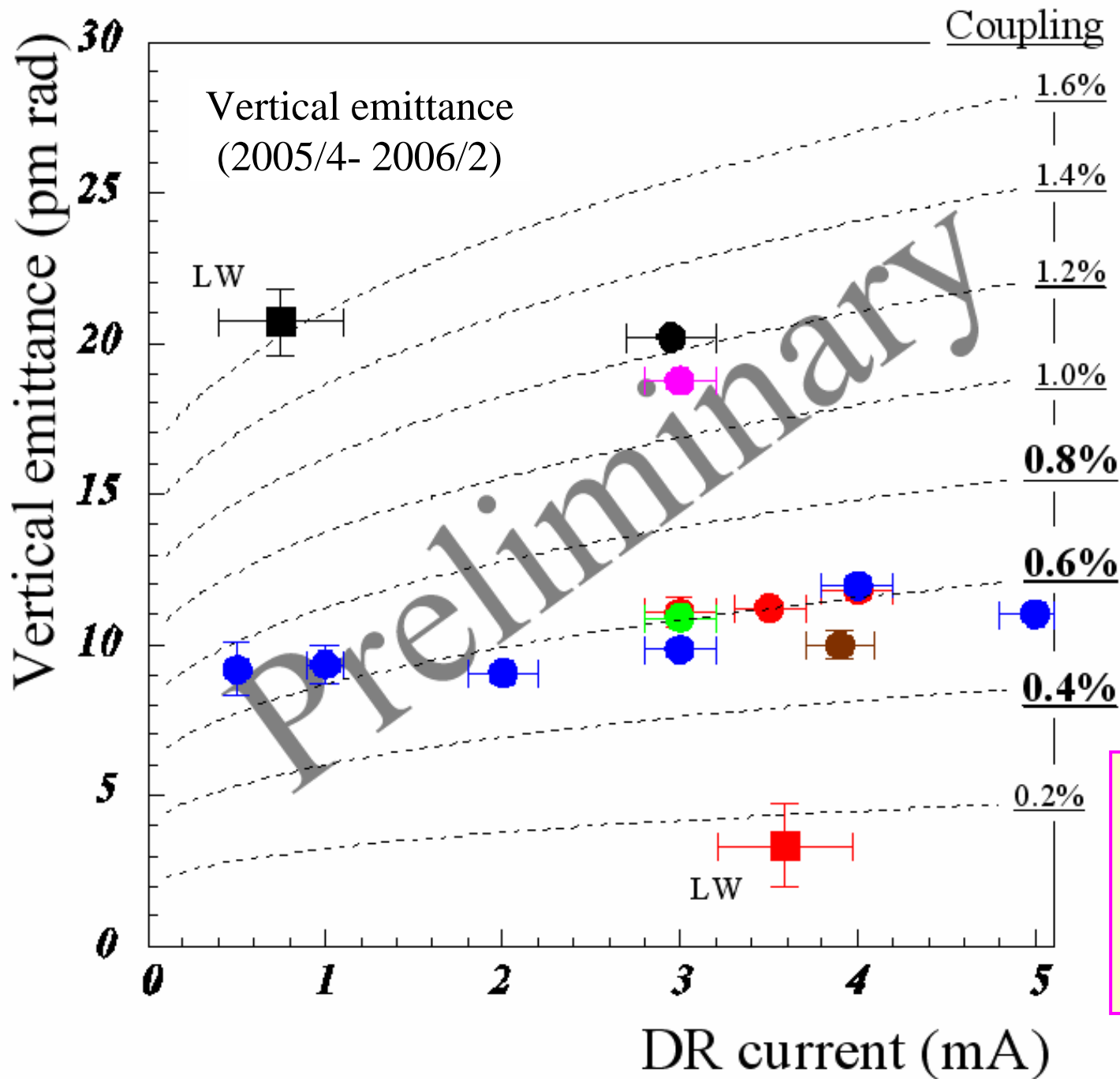


# Si monochromator effect

100Hz oscillation の原因を探るべく、Si monochromatorの電源を入れた状態(**on**)と切った状態(**off**)でbeam sizeに変化があるかどうかをshutter opening time (exposure time)を変えながら測定した。



Shutter timeに応じて垂直ビームサイズは同じように変化している。但し、Si monochromatorのon/offには全く依存していないのがわかる。  
→ビームサイズ増加はSi monochromatorでの振動のせいではない。これはsummer shutdown中に静電容量センサーで行った振動測定の結果と一致する。



Measured data

- : 2005/4/8 (XSR)
- : 2005/6/1 (XSR)
- : 2005/6/7 (XSR)
- : 2005/11/30 (XSR)
- : 2006/2/1 (XSR)
- : 2006/2/15 (XSR)
- : 2005/6/1 (LW)
- : 2006/2/15 (LW)

Laser wire size error is also included.

Dashed lines show the calculation of vertical emittance with intrabeam scattering effect on SAD by assuming coupling ratio